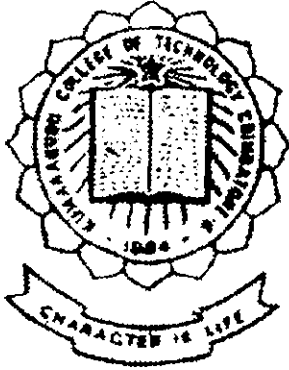


# AUTOMOTIVE VOLTAGE VARIATION TESTS

PROJECT WORK

P-358



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**PRICOL**  
Coimbatore.

**1999 - 2000**

*Submitted in partial fulfilment of the requirements  
for the award of the degree of*  
**BACHELOR OF ENGINEERING IN ELECTRONICS AND  
COMMUNICATION ENGINEERING**  
*Branch of the Bharathiar University*

DEPARMENT OF ELECTRONICS AND COMMUNICATION ENGINEERING

**KUMARAGURU COLLEGE OF TECHNOLOGY**

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**DEPARTMENT OF ELECTRONICS AND COMMUNICATION ENGINEERING**

**CERTIFICATE**

*This is to Certify that this Project Entitled  
**AUTOMOTIVE VOLTAGE VARIATION TESTS***

*has been submitted by*

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*in Partial fulfilment of the requirements for the award of the*

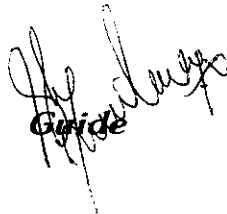
*Degree of*

**BACHELOR OF ENGINEERING IN ELECTRONICS AND**

**COMMUNICATION ENGINEERING of the**

**Bharathiyar University, Coimbatore-6.**

**during the academic year 1999-2000.**




**Guide**

**Head of the Department**

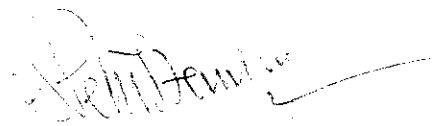
*Certified that the Candidate was examined by  
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*Viva Voce Examination held on .....*

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**Internal Examiner**



**External Examiner.**

## **SYNOPSIS**

In automobile Industry, the Electronic Instruments have many advantages over the existing Mechanical Instruments such as High reliability, Quality and accuracy. Also the Complexity of the Mechanical devices can be reduced by the use of Electronic devices.

These Electronic Instruments may be affected by the voltage variations generated by the Electrical loads such as lamps, horns, motors, etc., in automobiles.

If a battery is not charged perfectly, it drains, which results in variation of voltage levels.

So to test whether the Electronic circuits could withstand these voltage variations, the **“AUTOMOTIVE VOLTAGE VARIATION TESTS”** which generate three voltage waveforms, to the specifications of automobile Industries as per International Standard. Further it checks for any malfunctioning of the Electronic Instruments against the variation in battery voltages under certain test conditions.

The Voltage waveforms generated are applied to the electronic Instrument which is to be tested, along with the frequency signal to check for any malfunctioning of the Instrument.

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# **1. AUTOMOBILE ELECTRICAL SYSTEM**

The Electrical system of a modern automobile contain four main circuits as being the generating circuit, the starting circuit, the ignition circuit and the lighting circuit. Branches serve special purpose lights, audio, gasoline gage, heater, windshield wiper, defroster and several other accessory units. All the main circuits are connected together and linked to the battery as shown.

The starting or cranking motor is connected directly to the battery through cables and a switch to provide a low-resistance path for the large currents required by the motor.

The generating circuit ( generator and control) is connected to one end of the car ammeter, if there is one, so that the meter registers in the 'charge' direction when current is being sent to the battery. A wire connects the other end of the ammeter or the generator directly to the cable leading to the ungrounded pole of the battery.

The ignition primary circuit, the lighting circuit and all the branch circuits are connected to the same side of the ammeter as if the generator so that, when the generator is operating, they receive current directly from it without going through the ammeter. When

## **2. VOLTAGE VARIATION TESTS.**

As framed by many automobile industries as per the International Standards, three tests are to be conducted to check for any malfunctioning of the electronic instruments called as AUTOMOTIVE VOLTAGE VARIATION TESTS which has the following tests,

- a) Momentary Interruption of Power Test
- b) Supply Voltage Fluctuation Test I
- c) Supply Voltage Fluctuation Test II

### **3. MOMENTARY INTERRUPTION OF POWER TEST**

This test is conducted to check for any malfunctioning of the Instrument against possible variation in battery voltage , for instance at switching on the starter.

This has to carried out under the following conditions,

Voltage - 12volt

No. of cycles - 100 or more

Operating Conditions -

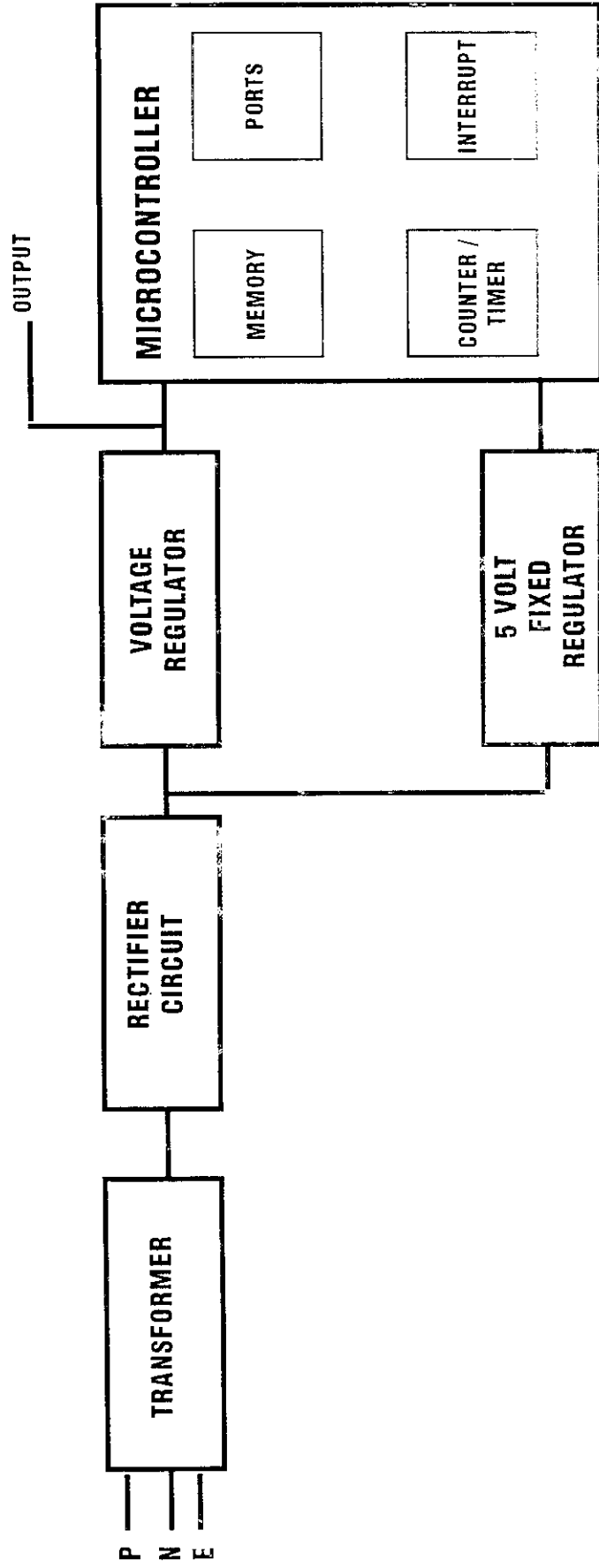
Speed - 0 Kmph

RPM- 0 rpm

Fuel - Full

Temperature- centre

### BLOCK DIAGRAM :





## **Circuit Description**

### **Transformer:**

A step down transformer is used whose input is 230v and output at 20v with 1amps current level.

### **Rectifier:**

This block uses Diodes which rectifies the output from transformer. It uses four diodes which are biased accordingly.

### **Voltage Regulator:**

The Voltage regulator outputs the voltage to a fixed level. 3v and 5v fixed Voltage regulators are used.

### **Micro Controller:**

The Micro Controller uses is ZILOG Z86E04 which is Programmed. It is an 8 be CMos, 18 Pin, 124 bytes of General purpose RAM, schmitt triggered micro controller.

## **4. SUPPLY VOLTAGE FLUTUATION TEST I**

This test is conducted to check for possible fluctuation in supply voltage;at startup of the starter, under the following test conditions.

Voltage - 12volt

No. of cycles - 1000 or more

Operating Conditions -

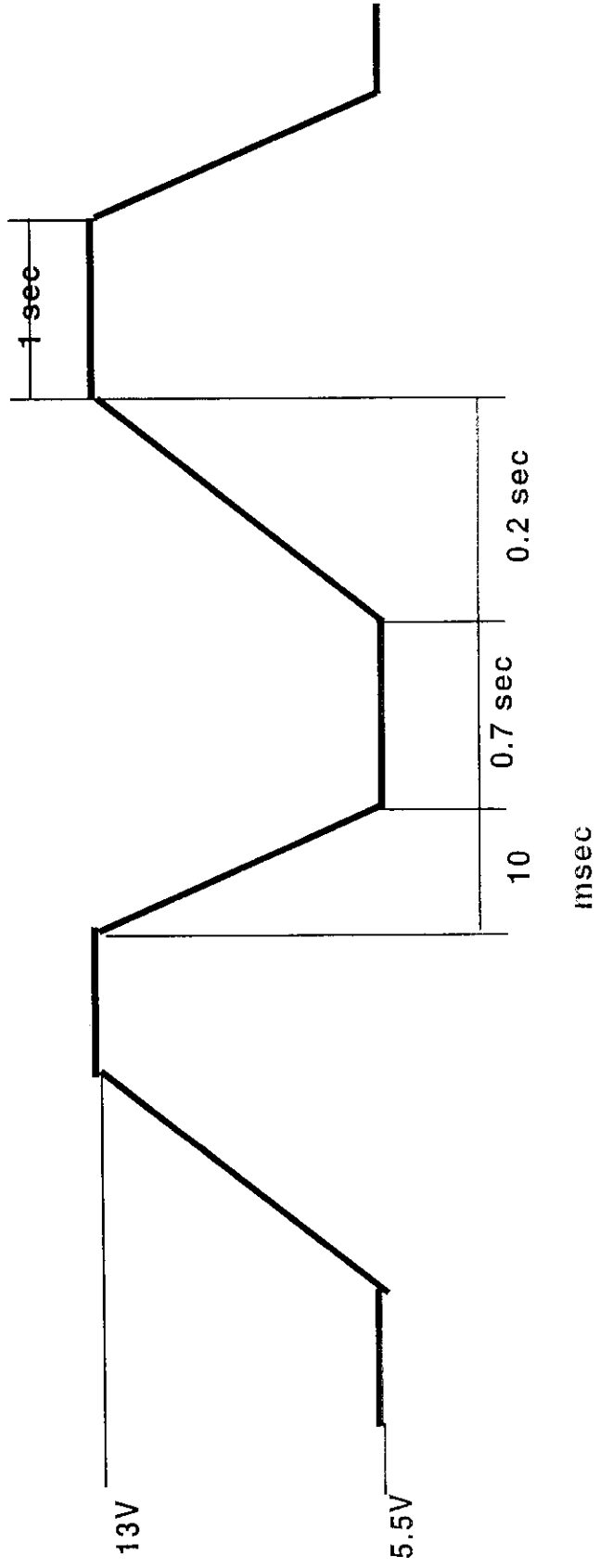
Speed - 0 Kmph

RPM- 0 rpm

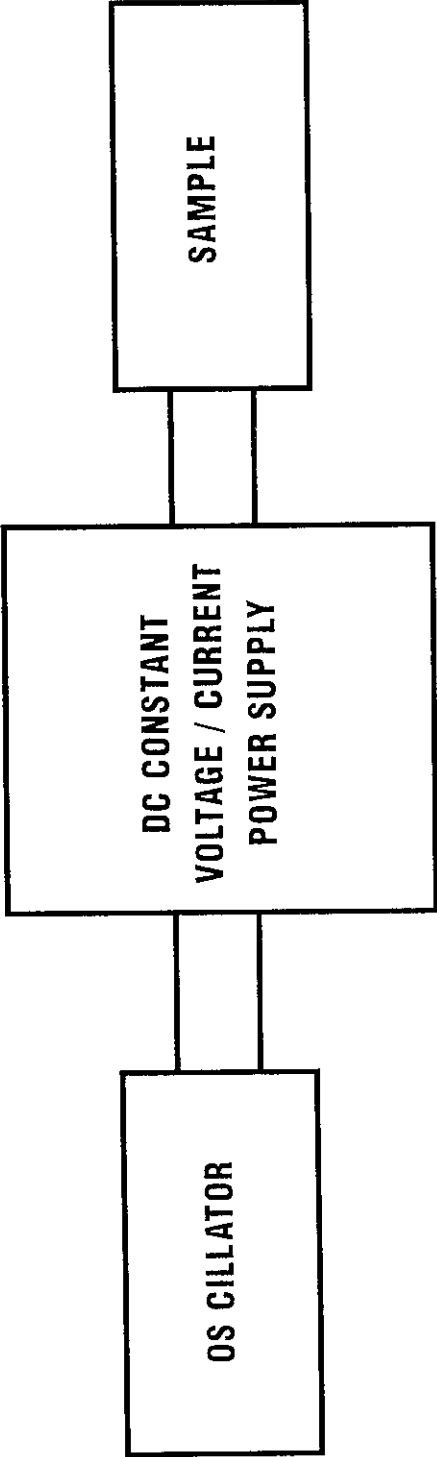
Fuel - Full

Temperature- centre

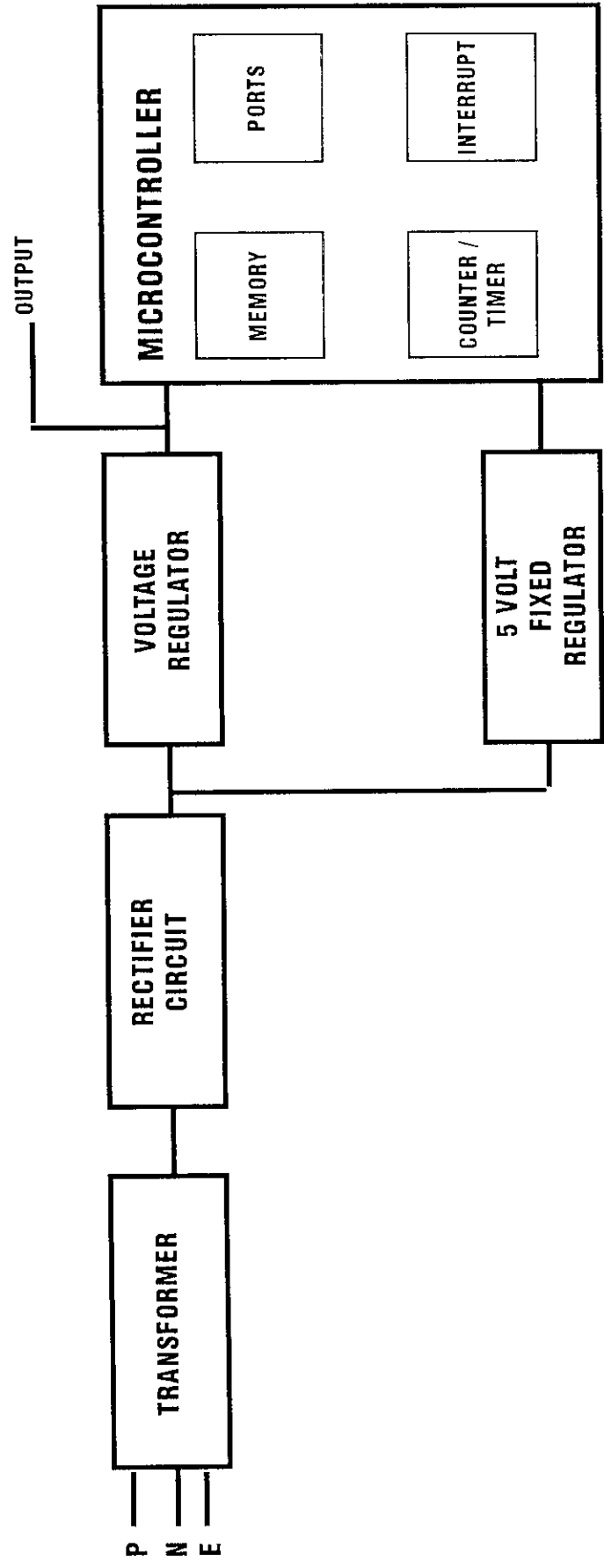
The Cyclic pattern of the test is shown below.



Applying the waveform to the line between the sample's power terminals, using the test circuit given below.



**BLOCK DIAGRAM :**



## **Circuit Description**

### **Transformer:**

A step down transformer is used whose input is 230v and output at 20v with 1amps current level.

### **Rectifier:**

This block uses Diodes which rectifies the output from transformer. It uses four diodes which are biased accordingly.

### **Voltage Regulator:**

The Voltage regulator outputs the voltage to a fixed level. 3v and 5v fixed Voltage regulators are used.

### **Micro Controller:**

The Micro Controller uses is ZILOG Z86E04 which is Programmed. It is an 8 be CMos, 18 Pin, 124 bytes of General purpose RAM, schmitt triggered micro controller.

## 5. SUPPLY VOLTAGE FLUTUATION TEST II

This test is conducted to check for possible fluctuations in supply voltage; including ripple voltage to be output from the generator, under the following test conditions.

Voltage - 12volt

No. of cycles - 1000 or more

Operating Conditions -

Speed - 0 Kmph

RPM- 0 rpm

Fuel - Full

Temperature- centre

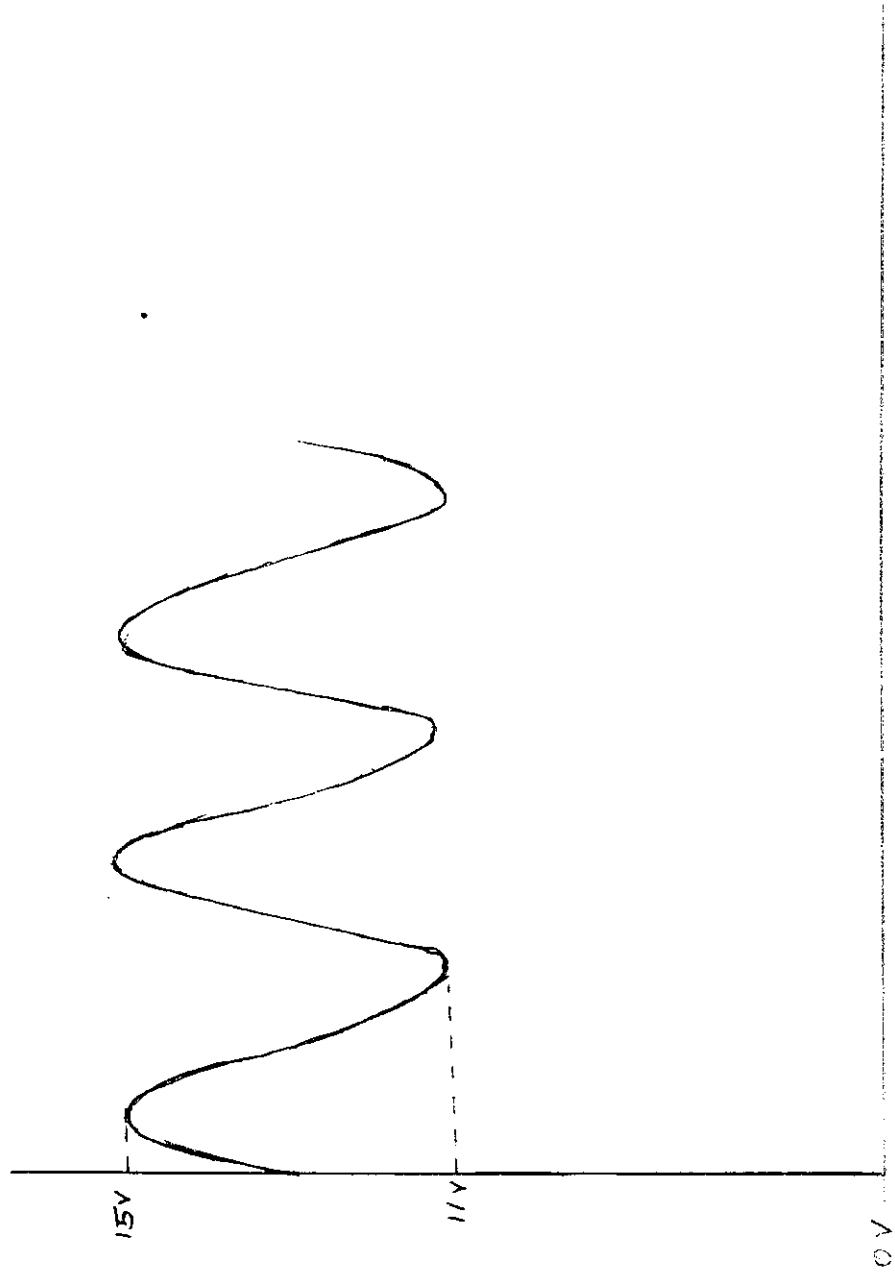
f -- ripple frequency to be fluctuated between 10 Hz and 10KHz during test.

**Vr-- #  $7 \pm 1v$**  for a product to be directly connected to the alternator output.

**$4 \pm 0.2v$**  for a product whose voltage is to supplied from a battery and includes a large ripple voltage.

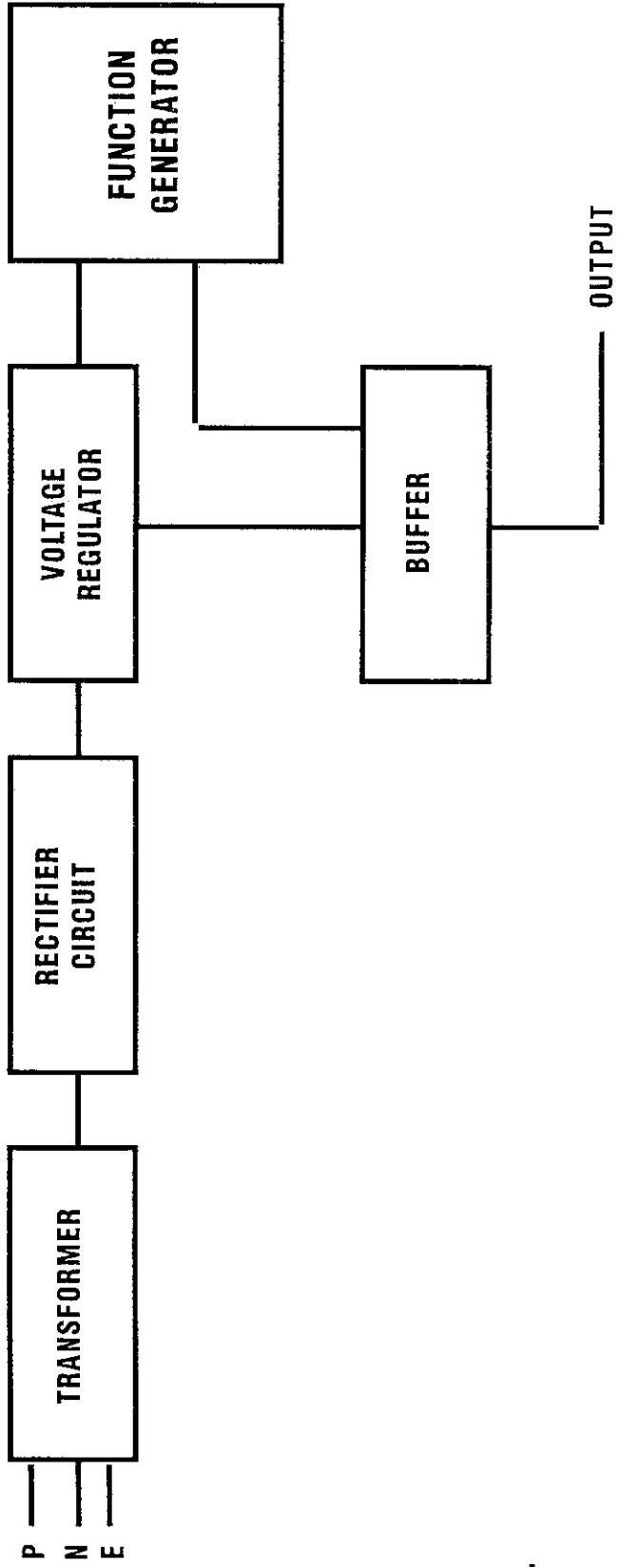
**$2 \pm 0.1v$**  for a product whose voltage to be supplied from a battery, but which is excluded from above.

The Cyclic pattern of the test is shown below.





**BLOCK DIAGRAM :**



## **Circuit Description**

### **Transformer:**

A step down transformer is used whose input is 230v and output at 20v with 1amps current level.

### **Rectifier:**

This block uses Diodes which rectifies the output from transformer. It uses four diodes which are biased accordingly.

### **Voltage Regulator:**

The Voltage regulator outputs the voltage to a fixed level. 3v and 5v fixed Voltage regulators are used.

### **Buffer:**

It is also caused as Driver circuit. The main function of an buffer is to amplify the voltage or current level. Here it acts as an current amplifier.

### **Function Generator:**

A 16 pin Monolithic function generator named XR2206. The main application of XR2206 is for waveform generation. The frequency of operation depends on timing Resistor and timing capacitor. Its frequency ranges from 0.001Hz to more than 1 Mhz.

2017

## 6. TEST SPECIFICATIONS

### Momentary Interruption of Power Test

Voltage - 12V  
Period - 2sec  
No. of cycles - 100 or more  
Operating Conditions -  
Speed - 0 Kmph  
RPM - 0 rpm  
Fuel - Full  
Temp - Center

### Supply Voltage Fluctuation Test I and II

Operating Conditions -  
Speed - 0 Kmph  
RPM - 0 rpm  
Fuel - Full  
Temp - Center

f -- ripple frequency to be fluctuated between 10 Hz and 10KHz during test.

Vr-- #  $7\pm 1v$  for a product to be directly connected to the alternator output.

$4\pm 0.2v$  for a product whose voltage is to supplied from a battery and includes a large ripple voltage.

$2\pm 0.1v$  for a product whose voltage to be supplied from a battery, but which is excluded from above.

## **7. MICROCONTROLLER**

### **Z86E04 OTP CMOS 8-BIT MICROCONTROLLER**

#### **FEATURES**

- ◆ 8-Bit CMOS Microcontroller
- ◆ 18-Pin DIP Package
- ◆ Low Noise Programmable
- ◆ ROM Protect Programmable
- ◆ 4.5 to 5.5 V Operating Range
- ◆ Low Power Consumption - 50 mW (Typical)
- ◆ Two Standby Modes - STOP and HALT
- ◆ 14 Input/Output Lines
- ◆ 124 Bytes of General Purpose RAM
- ◆ Six Vectored, Priority Interrupt from six different sources
- ◆ Clock Speed upto 8 MHz
- ◆ Watch-Dog Timer
- ◆ Power-On Reset
- ◆ Two On-Board Comparators
- ◆ Programmable Interrupt Polarity
- ◆ On-Chip Oscillator that accepts a Crystal, Ceramic Resonator.

## GENERAL DESCRIPTION

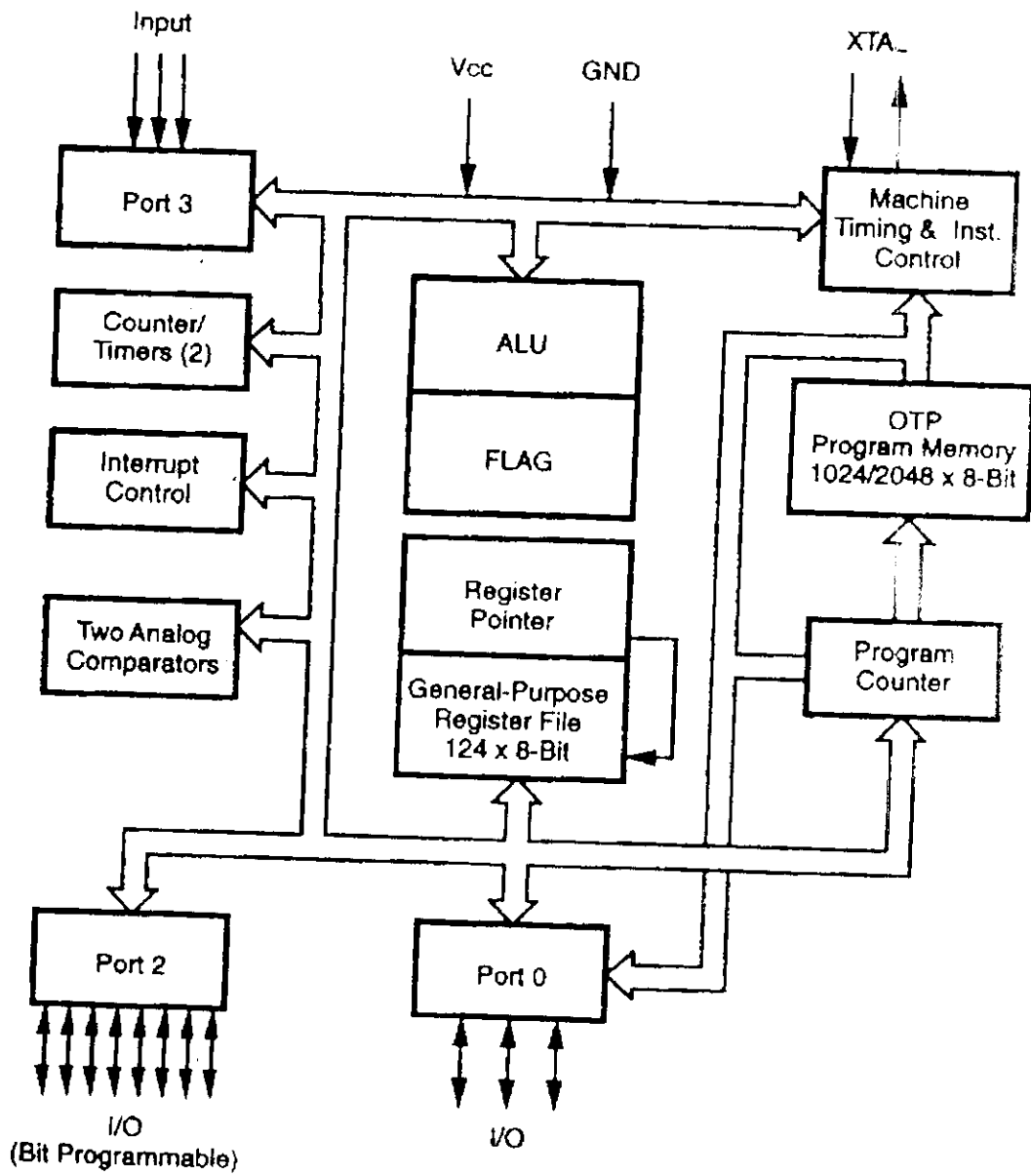
The Z86E04 microcontrollers introduce a new level of sophistication to single chip architecture. The Z86E04 is a member of the Z8 single chip microcontroller family with 1K bytes of one-time PROM . The device is housed in an 18-Pin DIP, and is manufactured in CMOS technology. The devices allow easy software development and debug, prototyping and small production runs not economically desirable with a masked ROM version.

The Z86E04 have a flexible I/O scheme, an efficient register and address space structure. Also, they have a number of ancillary features that are usefull in many consumer, industrial and commercial applications.

For applications which demand powerful I/O capabilities, the Z86E04 provide 14 pins dedicated to input and output. These lines are grouped into three ports, and are configurable under software control to provide I/O, timing and status signals.

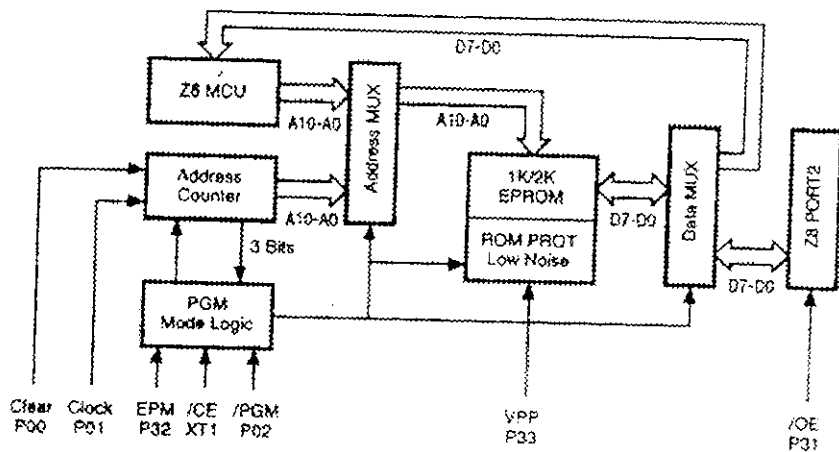
These are two basic address spaces available to support this wide range of configurations; program memory and 124 bytes of general-purpose registers.

The Z86E04 each offer programmable EPROM protect and programmable Low Noise. When the part is programmed for EPROM protect, the low Noise feature will automatically be enabled. When programmed for low noise, the EPROM protect feature is optional.

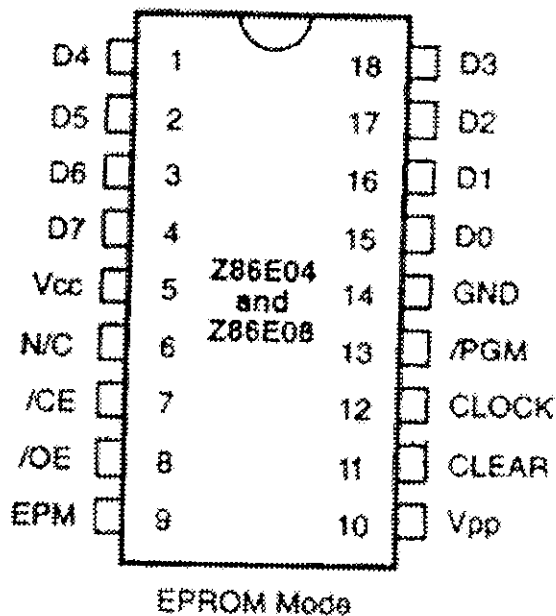


Functional Block Diagram

Fig. 3



EPROM MODE Block Diagram  
Fig. 4



EPROM MODE Pin Configuration  
Fig. 5

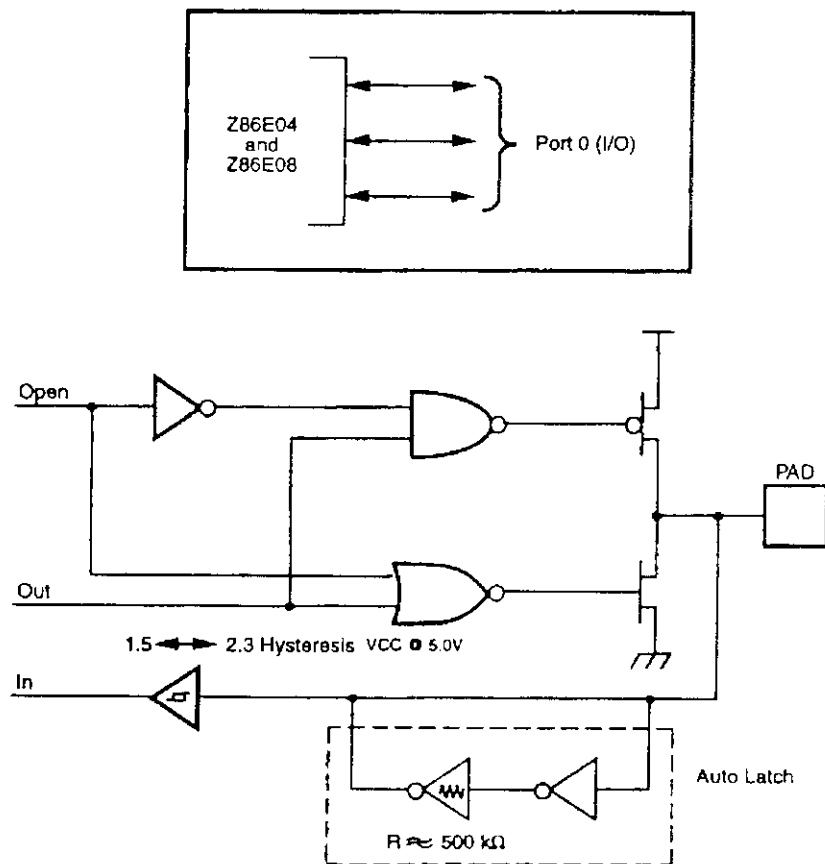
To understand the program from copying with real-time tasks such as counting/timing and I/O data communications, the Z86E04 offers two on-chip counter/timers with a large number of user selectable modes.



## PORTS

### PORT 0, P02-P00

Port 0 is a 3-bit bi-directional, Schmitt triggered CMOS compatible I/O port. These three I/O lines can be globally configured under software control to be an input or output.



**PORT 0 Configuration**

**Fig. 6**

## PORT 2, P27-P20

Port 2 is an 8-bit bidirectional, Schmitt triggered CMOS compatible I/O port. These eight I/O lines can be configured under software control to be input or output, independently. Bits programmed as outputs can be globally programmed as either Push-Pull or Open Drain.

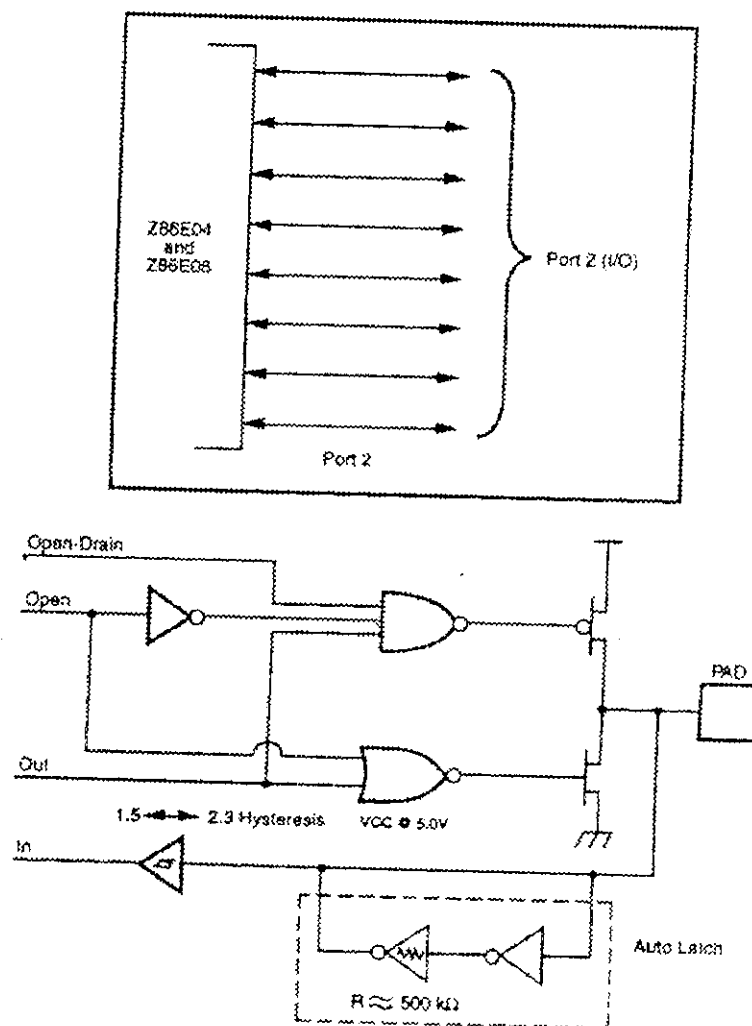
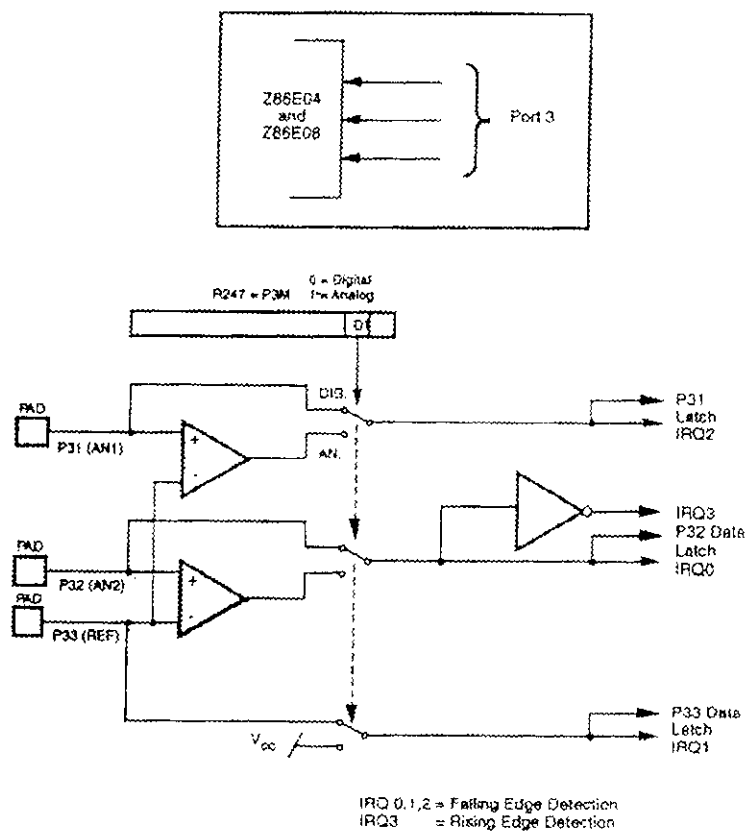


Figure 7. Port 2 Configuration

Fig. 7

## PORT 3, P33-P31

Port 3 is a 3-bit CMOS compatible port with three fixed input lines. These three input lines can be configured under software control as digital inputs or analog inputs. These three input lines are also used as the interrupt sources IRQ0-IRQ3 and as the timer input signal.



PORT 3 Configuration

Fig. 8

## **COMPARATOR INPUTS**

Two analog comparators are added to input of port3, P31 and P32 for interface flexibility. The Comparator reference voltage P3 is common to both comparators.

Typical applications for the on-board comparators; Zero crossing detector, A/D convertor, voltage scaling and threshold detection. In analog mode, P33 input functions serve as a reference voltage to the comparator.

The dual comparator features a single power supply which discontinues power in STOP mode. The common voltage range is 0-4V when the Vcc is 5V; the power supply and common mode rejection ratios are 90dB and 60dB respectively.

## **PROGRAM MEMORY**

The Z86E04 addresses upto 1Kbytes of the internal program memory. The first 12 bytes of program memory are reserved for the interrupt vectors. These locations contain six 16-bit vectors that correspond to the six available interrupts. Bytes 0-1024 are on-chip one time programmable ROM.

## **REGISTER FILE**

The Register file consists of three I/O port registers, 124 general-purpose registers and 14 control and status registers. General purpose registers occupy the 04H to 7FH address space. I/O

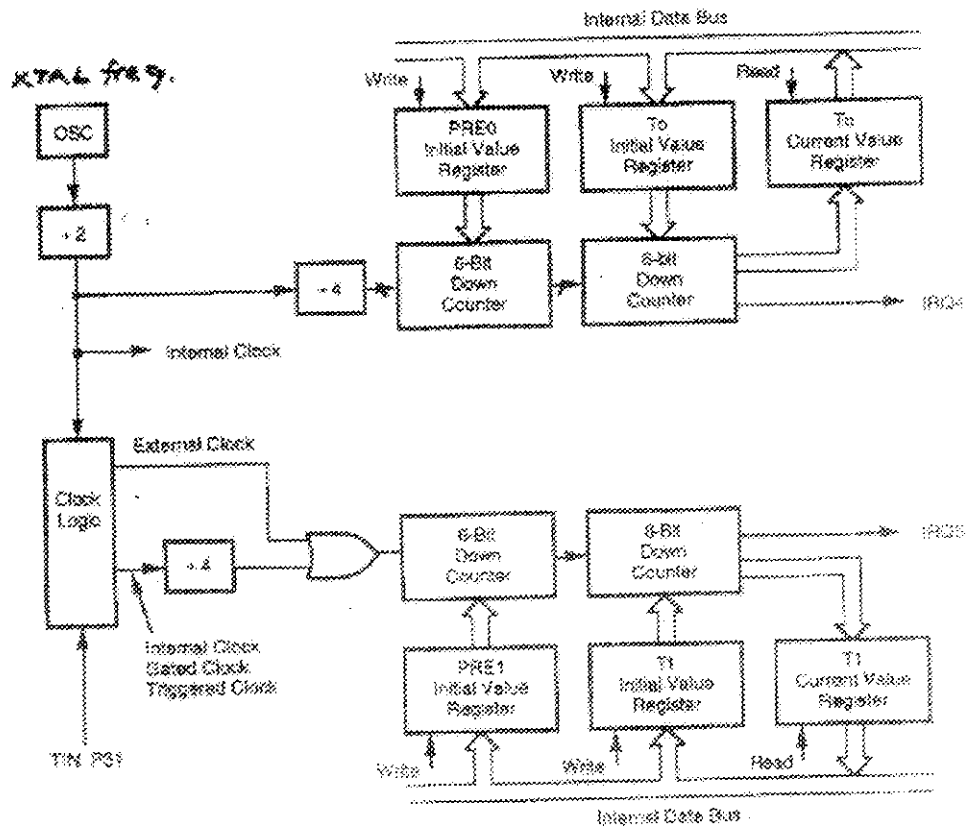
ports are mapped as per the existing CMOS Z8. The Z86E04 instructions can access registers directly or indirectly through an 8-bit address field. This allows short 4-bit register addressing using the register Pointer. In the 4-bit mode the register file is divided into eight working register groups, each occupying 16 continuous locations. The register Pointer addresses the starting location of the active working-register group.

## **COUNTER/TIMER**

There are two 8-bit programmable Counter/Timers, each divided by its own 6-bit programmable prescaler. The T1 prescaler is divided by internal or external clock source; however, the T0 can be divided by the internal clock source only.

The 6-bit prescaler divide the input frequency of the clock source by any integer number from 1 to 64. Each prescaler drives its counter, which decrements the value that has been loaded into the counter. When both counter and prescaler reach the end of count, a timer interrupt request IRQ4 (T0) or IRQ5 (T1) is generated.

The counter can be programmed to stop, restart, continue or restart from the initial value. The counter's are also programmed to stop upon reaching zero or to automatically reload the initial value and continue counting.



**COUNTER / TIMERS Block Diagram**

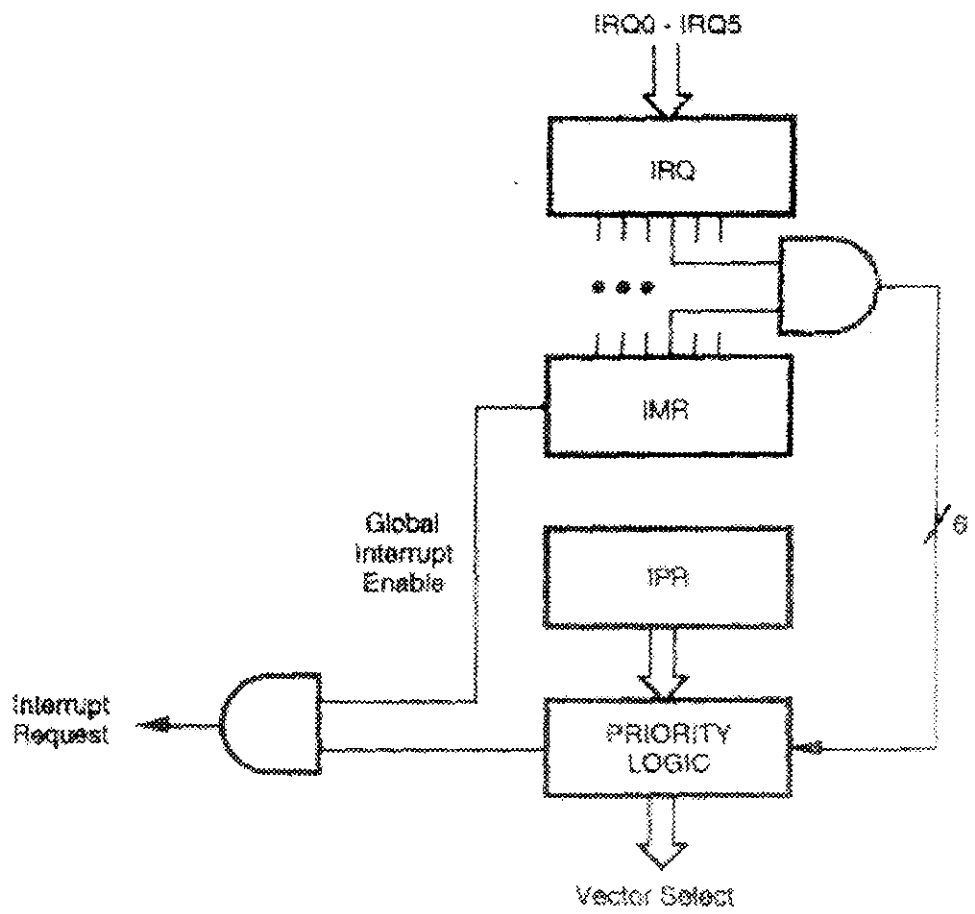
**Fig. 9**

## INTERRUPTS

The Z86E04 has six interrupts from five different sources. These interrupts are maskable and prioritized. The sources are divided as follows: the falling edge of P31,P32,P33. The interrupt Mask register globally or individually enables or disables the six interrupt requests.

When more than one interrupt is pending, priorities are resolved by a programmable priority encoder that is controlled by the Interrupt Priority register. All Z86E04 interrupts are vectored through locations in program memory. When an interrupt machine cycle is activated, an interrupt Request is granted. This disables all subsequent interrupts, saves the program Counter and Status Flags, and then branches to the program memory vector location reserved for that interrupt. This memory location and the next byte contain the 16-bit starting address of the interrupt service for the particular interrupt request.

To accommodate polled interrupt systems, interrupt inputs are masked and the interrupt request register is polled to determine which of the interrupt request needs service.



INTERRUPT Block Diagram

Fig. 10



## **CLOCK**

The Z86E04 on-chip oscillator has a high gain, parallel - resonant amplifier for connection to a crystal, ceramic resonator, or any suitable external clock source. The crystal should be AT cut, 8MHz max, with a series resistance of less than or equal to 100 ohms.

The Crystal should be connected accross XTAL1 and XTAL2, using the vendors crystal recommended capacitors from each pin directly to device grounded pin. The crystal capacitor loads should be connected to Vss, pin 14 to reduce Ground noise injection.

## **HALT MODE**

Turns off the internal CPU clock but not the cryatal oscillation. The counter/timers and external interrupts remains active. The device is recovered by interrupts, eitherexternally or internally generated. An interrupt service routine, the program continues from the instruction after the HALT

## **STOP MODE**

This instruction turns off the internal clock and external crystal oscillation and reduces the standby current to 10uA. The STOP mode is released by a RESET through a Stop-Mode recovery. A low input condition on P27 releases the STOP mode. Program execution begins at location 000C. However, when P27 is used to release the STOP mode, the I/O port mode registers are not

reconfigured to their default power-on conditions. This prevents any I/O, configured as output when the STOP instruction was executed, from glitching to an unknown state.

## **WATCH-DOG TIMER**

The Watch-Dog Timer is enabled by instruction WDT. When the WDT is enabled, cannot be stopped by the instruction. With the WDT instruction, the WDT is refreshed when it is enabled with every 1Twdt period; otherwise, the Z86E04 resets itself. The WDT instruction affects the flags accordingly; Z=0, S=0, V=0.

WDT = 5F (Hex)

## **LOW EMI EMISSION**

The Z86E04 can be programmed to operate in a low EMI emission mode by means of a EPROM programmable bit option. Use of this feature results in

- ◆ Less than 1 mA consumed during HALT mode.
- ◆ All drivers slew rates reduced to 10 ns.
- ◆ Output drivers have resistances of 200 ohms.
- ◆ Oscillator divide-by-two circuitry eliminated.

The Z86E04 offers programmable ROM protect and programmable Low noise features. When programmed to Low noise, the ROM protect feature is Optional.

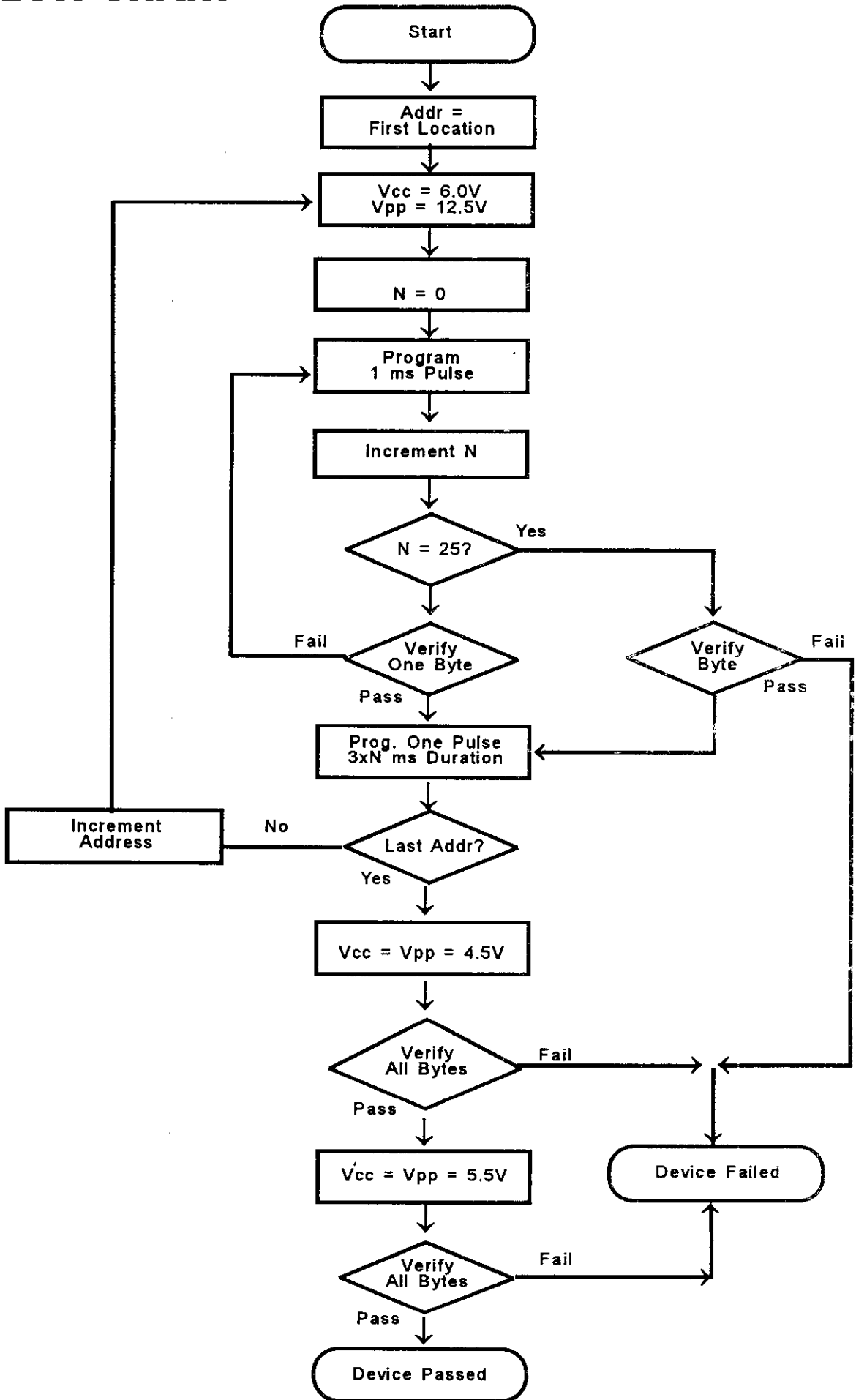
## **ROM PROTECT**

ROM Protect fully protects the Z86E04 ROM code from being read externally. When the ROM protect is selected, the Z86E04 will disable the instructions LDC and LDCI. When the device is programmed for ROM protect, the low noise feature will automatically be enabled.

## **ALGORITHM :**

1. Start
2. Initialise first byte address location
3. Let count = 0
4. Apply delay
5. Increment count
6. Check for last address byte or else increment address
7. Verify all bytes to find device passed or failed.

# FLOW CHART



## 8. SOFTWARE

```
;          SOFTWARE FOR MOMENTARY INTERRUPTION OF  
POWER TEST
```

```
;          STANDARD DENSO
```

```
;          IC 86 E 04 ZILOG
```

```
;          CRYSTAL 8 MHZ
```

```
;          PROGRAMME START
```

```
.;*****  
;
```

```
          CPU "Z8.tb!"
```

```
          HOF "int8"
```

```
;Standard control registers:
```

```
P0   :          EQU    00H  
P2   :          EQU    02H  
P3   :          EQU    03H  
TMR  :          EQU    0F1H  
T1   :          EQU    0F2H  
PRE1 :          EQU    0F3H  
T0   :          EQU    0F4H  
PRE0 :          EQU    0F5H  
P2M  :          EQU    0F6H  
P3M  :          EQU    0F7H
```

P01M :	EQU	0F8H
IPR :	EQU	0F9H
IRQ :	EQU	0FAH
IMR :	EQU	0FBH
FLAGS:	EQU	0FCH
RP :	EQU	0FDH
SPL :	EQU	0FFH
SPH :	EQU	0FEH
WDTMR:	EQU	00FH
SMR:	EQU	00BH

bit0: EQU 1h

bit1: EQU 2h

bit2: EQU 4h

bit3: EQU 8h

bit4: EQU 10h

bit5: EQU 20h

bit6: EQU 40h

bit7: EQU 80h

nbit0: EQU 0feh

nbit1: EQU 0fdh

nbit2: EQU 0fbh

nbit3: EQU 0f7h

nbit4: EQU 0efh

nbit5: EQU 0dfh

nbit6: EQU 0bfh

nbit7: EQU 7fh

```
position1 : EQU01h
position2 : EQU02h
position3 : EQU03h
```

```
running_bit : EQUbit0
test_prog_bit : EQUbit0
test_comp_bit : EQUbit1
```

```
;General purpose register equates-
```

```
ctr : equ 4
addr_ctr : equ 5
COUNT : equ 6
POSITION : equ 7
START_DEBOUNCER: equ 8
RESET_DEBOUNCER: equ 9
TIMER : equ 10
TIMER_10 : equ 11
FLAG1: equ 12
CYCLE_COUNT: equ 13
```

```
;equate interrupt vectors
```

```
ORG 0
DWM start

ORG 2
DWM start

ORG 4
DWM start
```



```

ORG 6
DWM start

ORG 8
DWM t0_isr ;dis_int

ORG 10
DWM start ;timer interrupt T1

ORG 12

```

```
start:
```

```

nop
nop
nop
srp #0f0h
ldr spl-240 , #070h
ldr sph-240, #0
call initialize
call init_ram

```

```
start1:
```

```

wdt
call switch_check
jp start1

```

```
initialize:
```

```

ldr p3m-240 , #00000001b
ldr p2m-240 , #00000000b
ldr p01m-240 , #00000100b
ldr tmr-240 , #00000011b ;2ch
ldr t0-240 , #250
ldr pre0-240 , #00000101b ;prescaler 1 - 20
; ldr ipr-240 , #00100111b

```

```

        ldr imr-240 , #00010000b
        ldr irq-240 , #00000000b
        srp #0
        ret
init_ram:
        wdt
        ldr ctr , # 60
        ldr addr_ctr , # 0
loop20:
        ld 4 ( rctr ) , raddr_ctr
        djnzr ctr , loop20
        clr FLAG1
        clr TIMER
        clr TIMER_10
        clr CYCLE_COUNT
        ld p2, #0
        ld p0, #0
        ld START_DEBOUNCER, #10
        ld RESET_DEBOUNCER, #10
        and FLAG1, #nbit0 ;running_bit
        ret
switch_check:
        tm FLAG1, #running_bit
        jr nz, switch_check_ret
        tm p3, #bit1
        jr z, switch_check_ret
        dec START_DEBOUNCER
        jr nz, switch_check_ret

```

```

ei
or   imr, #90h
ld   POSITION, #position1
or   FLAG1, #running_bit
or   p0, #test_prog_bit
and  p0, #nbit1           ;clr test_comp_bit
ld   COUNT, #3
ld   p2, #0ffh
ld   START_DEBOUNCER, #10
ret

```

switch\_check\_ret:

```

tm   p3, #bit2
jr   z, switch_check_ret1
dec  RESET_DEBOUNCER
jr   nz, switch_check_ret1
ld   p2, #0
di
clr  CYCLE_COUNT
and  p0, #nbit1           ;clr test_comp_bit
and  p0, #nbit0           ;test_prog_bit
and  FLAG1, #nbit0       ;running_bit
ld   RESET_DEBOUNCER, #10

```

switch\_check\_ret1:

```
ret
```

t0\_isr:

```
inc  TIMER
cp   TIMER, #40

```

```

    jr    c, isr_ret
    clr  TIMER
;   xor  p0, #bit2
    inc  TIMER_10
    cp   POSITION, #position1
    jr   nz, isr1
    clr  TIMER
    dec  COUNT
    jr   nz, isr_ret
    and  p2, #nbit0
    ld   POSITION, #position2
    ld   COUNT, #6
    jp   isr_ret
isr1:
    cp   POSITION, #position2
    jr   nz, isr2
    rcf
    rlc  p2
    clr  TIMER
    dec  COUNT
    jr   nz, isr_ret
    ld   POSITION, #position3
    clr  TIMER_10
    jp   isr_ret
isr2:
    cp   TIMER_10, #1
    jr   ugt, isr3

```

```
or p0, #bit2
```

```
jp isr4
```

```
isr3:
```

```
and p0, #nbit2
```

```
isr4:
```

```
cp TIMER_10, #200
```

```
jr c, isr_ret
```

```
clr TIMER
```

```
clr TIMER_10
```

```
ld COUNT, #3
```

```
ld p2, #0ffh
```

```
ld POSITION, #position1
```

```
inc CYCLE_COUNT
```

```
cp CYCLE_COUNT, #100
```

```
jr c, isr_ret
```

```
and p0, #nbit0 ;test_prog_bit
```

```
or p0, #test_comp_bit
```

```
clr CYCLE_COUNT
```

```
di
```

```
and imr, #6fh
```

```
ld p2, #0
```

```
and FLAG1, #nbit0 ;running_bit
```

```
isr_ret:
```

```
iret
```

;SUPPLY VOLTAGE FLUCTUATION TEST

;STANDARD DENSO

;IC 86 E 04

;CRYSTAL OSC 8MHZ

CPU "Z8.tbl"

HOF "int8"

;Standard control registers:

P0	:	EQU	00H
P2	:	EQU	02H
P3	:	EQU	03H
TMR	:	EQU	0F1H
T1	:	EQU	0F2H
PRE1	:	EQU	0F3H
T0	:	EQU	0F4H
PRE0	:	EQU	0F5H
P2M	:	EQU	0F6H
P3M	:	EQU	0F7H
P01M	:	EQU	0F8H
IPR	:	EQU	0F9H
IRQ	:	EQU	0FAH
IMR	:	EQU	0FBH
FLAGS	:	EQU	0FCH
RP	:	EQU	0FDH
SPL	:	EQU	0FFH
SPH	:	EQU	0FEH
WDTMR	:	EQU	00FH
SMR	:	EQU	00BH

bit0: EQU 1h  
bit1: EQU 2h  
bit2: EQU 4h  
bit3: EQU 8h  
bit4: EQU 10h  
bit5: EQU 20h  
bit6: EQU 40h  
bit7: EQU 80h

nbit0: EQU 0feh  
nbit1: EQU 0fdh  
nbit2: EQU 0fbh  
nbit3: EQU 0f7h  
nbit4: EQU 0efh  
nbit5: EQU 0dfh  
nbit6: EQU 0bfh  
nbit7: EQU 7fh

position1: EQU 01h  
position2: EQU 02h  
position3: EQU 03h  
position4: equ 04h

running\_bit: EQU bit0  
test\_prog\_bit: EQU bit0  
test\_comp\_bit: EQU bit1

;General purpose register equates-

ctr: equ 4

addr\_ctr: equ 5

COUNT: equ 6

POSITION: equ 7

START\_DEBOUNCER: equ 8

RESET\_DEBOUNCER: equ 9

TIMER: equ 10

FLAG1: equ 11

TIMER\_16: equ 12

TIMER1\_16: equ 13

CYCLE\_COUNT: equ 14

rr12: equ 12

;equate interrupt vectors

ORG 0

DWM start

ORG 2

DWM start

ORG 4

DWM start

ORG 6

DWM start

org 8

DWM t0\_isr ;dis\_int

ORG 10

DWM start ;timer interrupt T1

ORG 12



start:

```
    nop
    nop
    nop
    srp #0f0h
    ldr spl-240 , #070h
    ldr sph-240, #0
    call initialize
    call init_ram
```

start1:

```
    wdt
    call switch_check
    jp  start1
```

initialize:

```
    ldr p3m-240 , #00000001b
    ldr p2m-240 , #00000000b
    ldr p01m-240 ,#00000100b
    ldr tmr-240 , #00000011b
    ldr t0-240 , #160
    ldr pre0-240 ,#00000101b
    ldr imr-240 , #00010000b
    ldr irq-240 , #00000000b
    srp #0
    ret
```

init\_ram: ;RAM CLEAR

```
    wdt
    ldr ctr , # 60
    ldr addr_ctr , # 0
```

```

loop20:
    ld    4 ( rctr ) , raddr_ctr
    djnzr ctr , loop20
    clr  FLAG1
    clr  TIMER
    clr  TIMER_16
    clr  TIMER1_16
;   clr  CYCLE_COUNT
    ld  p2, #0
    ld  p0, #0
    ld  START_DEBOUNCER, #10
    ld  RESET_DEBOUNCER, #10
    and FLAG1, #nbit0          ;running_bit
    ret

```

```

switch_check:                                ;START SENSE
    tm  FLAG1, #running_bit
    jr  nz, switch_check_ret
    tm  p3, #bit1
    jr  z, switch_check_ret
    dec START_DEBOUNCER          ; DELAY LOOP
    jr  nz, switch_check_ret
    ei
    or  imr, #90h
    ld  POSITION, #position1
    or  FLAG1, #running_bit
    or  p0, #test_prog_bit

```

```

    and p0, #nbit1          ;clr test_comp_bit
    ld  COUNT,#5
;   ld  p2, #0ffh
    ld  p2, #01h
    ld  START_DEBOUNCER, #10
    ret

```

switch\_check\_ret:

```

    tm  p3, #bit2
    jr  z, switch_check_ret1
    dec RESET_DEBOUNCER
    jr  nz, switch_check_ret1
    ld  p2, #0
    di
    clr CYCLE_COUNT
    or  p0, #bit1          ;clr test_comp_bit
    and p0, #nbit0        ;test_prog_bit
    and FLAG1, #nbit0     ;running_bit
    ld  RESET_DEBOUNCER, #10

```

switch\_check\_ret1:

```

    ret

```

t0\_isr:

```

    inc TIMER
    cp  TIMER, #10
    jr  c, isr_ret
    clr TIMER
    incw rr12      ;1.6ms

```

```

    cp    POSITION, #position1
    jr    nz, isr1
    scf
    rlc   p2
    dec   COUNT
    jr    nz, isr_ret
    ld    POSITION, #position2
;   ld    COUNT, #6
    clr   TIMER_16
    clr   TIMER1_16
    jp    isr_ret
isr1:
    cp    POSITION, #position2
    jr    nz, isr2
    cp    TIMER_16, #1h
    jr    c, isr_ret
    cp    TIMER1_16, #0eeh
    jr    c, isr_ret
    rcf
    rlc   p2
    ld    POSITION, #position3
    clr   TIMER_16
    clr   TIMER1_16
    ld    COUNT, #5
    jp    isr_ret
isr2:
    cp    POSITION, #position3
    jr    nz, isr5
    cp    TIMER1_16, #21
    jr    c, isr_ret
    rcf

```

```

    rlc  p2
    clr  TIMER_16
    clr  TIMER1_16
    dec  COUNT
    jr   nz, isr_ret
    ld   POSITION, #position4
    jr   nz, isr_ret
isr5:
    cp   TIMER_16, #2h
    jr   c, isr_ret
    cp   TIMER1_16, #71h
    jr   c, isr_ret
    clr  TIMER
    clr  TIMER_16
    clr  TIMER1_16
    ld   COUNT, #5
;   ld   p2, #0ffh
    scf
    rlc  p2
    ld   POSITION, #position1
;   inc  CYCLE_COUNT
;   cp   CYCLE_COUNT, #100
;   jr   c, isr_ret
;   and  p0, #nbit0           ;test_prog_bit
;   or   p0, #test_comp_bit
;   clr  CYCLE_COUNT
;   di
;   and  imr, #6fh
;   ld   p2, #0
    and  FLAG1, #nbit0       ;running_bit
isr_ret:
    iret

```

## **9. FUNCTION GENERATOR**

### **FEATURES**

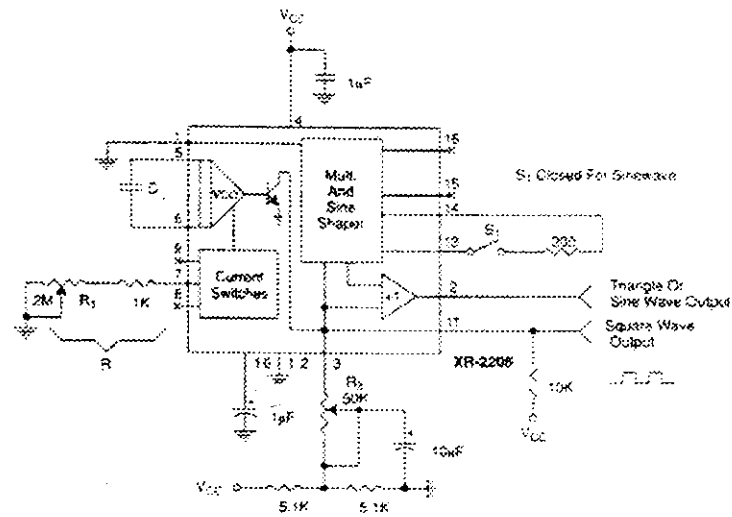
- ◆ Low- sine wave Distortion
- ◆ Excellent Temperature Stability
- ◆ Wide Sweep Range
- ◆ Low-Supply Sensitivity
- ◆ Linear Amplitude Modulation
- ◆ TTL compatible FSK Controls
- ◆ Wide Supply Range
- ◆ Adjustable Duty Cycle

### **APPLICATIONS**

- ◆ Waveform Generation
- ◆ Sweep Generation
- ◆ AM/FM Generation
- ◆ V/F Conversion
- ◆ FSK Generation
- ◆ Phase-Locked Loops (VCO)

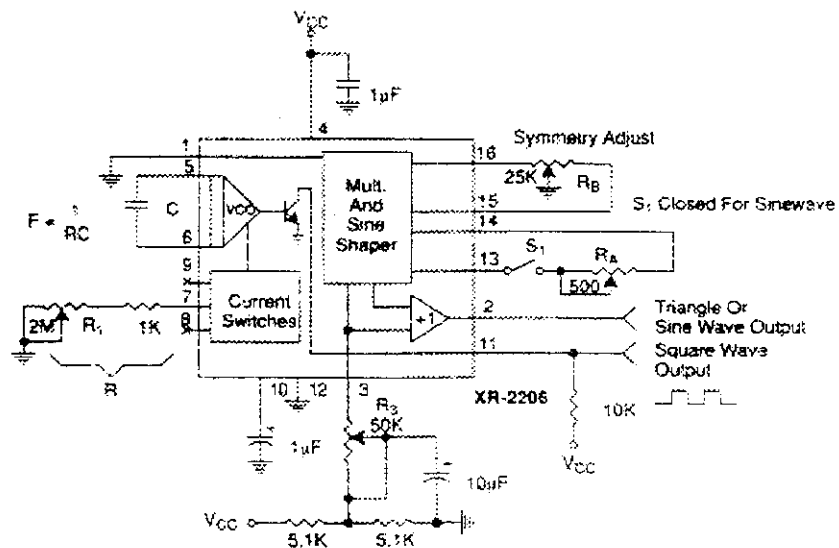
# CIRCUIT FOR SINEWAVE GENERATION

Temperature.



Without External Adjustment

Fig. 12



With Minimum Harmonic Distortion

Fig. 13

# 10. VOLTAGE REGULATORS

## 3-TERMINAL POSITIVE REGULATORS (7805)

### FEATURES

- ◆ Output voltage tolerances of  $\pm 5\%$
- ◆ Output current of 100mA
- ◆ Internal thermal overload protection
- ◆ Internal Shortcircuit current limit

### GENERAL DESCRIPTION

The LM7805, three terminal positive regulators is available with several fixed output voltages making them useful in a wide range of applications. When used as a Zener diode/ resistor combination replacement, the LM7805 usually results in an effective output impedance improvement of two orders of magnitude and lower quiescent current. These regulators can provide local on-card regulation, eliminating the distribution problems associated with single point regulation. The voltages available allow the LM7805 to be used in logic systems, instrumentation, HiFi and other solid state electronic equipment. Although designed primarily as fixed voltage regulators these devices can be used with external components to obtain adjustable voltages and currents.

With adequate Heat sinking the regulator can deliver 100mA output current. Current limiting is included to limit the peak output current to a safe value. Safe area protection for the output transis-



## 11. FABRICATION

The Automotive Voltage Variation Tests that comprises of the three voltage waveform generating circuits (PCBs) are placed inside a single setup. The whole test equipment consists of five blocks namely

- ◆ CRO - 10MHz Dual Scope Oscilloscope.
- ◆ Momentary Interruption of Power Test Block
- ◆ Supply Voltage Flutuation Test I Block
- ◆ Supply Voltage Flutuation Test II Block
- ◆ Voltage and Current Measuring Block

The three Voltage waveform generating circuits, generates their respective Voltage waveforms and can be viewed by a CRO placed at the top of the equipment. The Lower part of the equipment has a Voltmeter and Ammeter to detect for any shortcircuit , so that it could be rectified.

The three Voltage blocks are faciliated with

- ◆ Test ON/OFF Switch
- ◆ Output Signal Knobs
- ◆ Start Button
- ◆ Stop Button
- ◆ Test on Process Indication
- ◆ Test Completed Indication.

## **12. ADVANTAGES**

### **ADVANTAGE OF USING ELECTRONICS**

- Low Cost
- High Reliability
- Improvement in Efficiency
- Accuracy
- High Quality
- Less Complexity

### **ADVANTAGE OF AUTOMOTIVE VOLTAGE VARIATION TESTS :**

- Used to check for any Malfunctioning of the electronic Instrument against possible variation in battery voltage.
- Used to check for possible Fluctuation in supply voltage; including ripple voltage to be output from the generator.
- Used to check for possible Fluctuation in supply voltage at Startup of the Starter.

## **13. CONCLUSION**

Our Project "AUTOMOTIVE VOLTAGE VARIATION TESTS" is designed for use in all vehicle testing. The Automotive Voltage Variation test equipment is a device suitable for International Standards. The value of the Voltage levels in the waveform are quite accurate. The Automotive voltage variation Tests equipment is designed in such a way that facilities available at present can be expanded.

This Project can be expended by including all the electrical loads like horns motors etc., and their Voltage and Current level can be monitored from the Volt meter and Ammeter fitted below and can be tested. Further A PC can be attached so that the waveform can be stored and printed out.

## **14. BIBLIOGRAPHY**

1. ZILOG MICROCONTROLLER DATA BOOK
2. LINEAR IC DATA BOOK - NATIONAL SEMICONDUCTOR
3. AUTOMOTIVE MECHANICS - JOSEPH HEITNER
4. EXAR DATA BOOK
5. NATIONAL SEMICONDUCTOR DATA BOOK

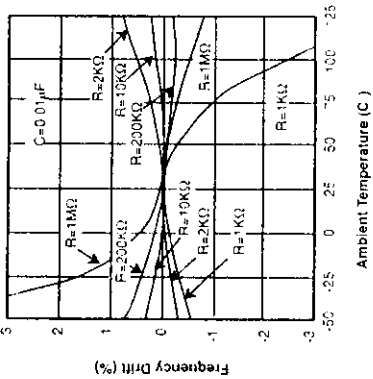


Figure 9. Frequency Drift versus Temperature.

Figure 10. Circuit Connection for Frequency Sweep.

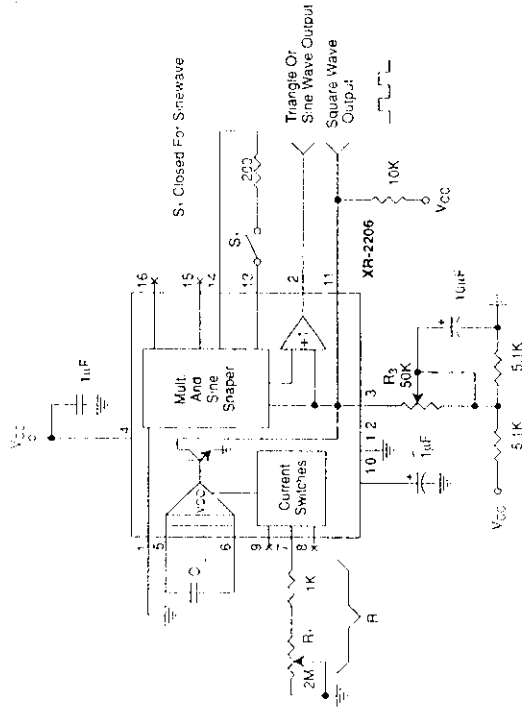
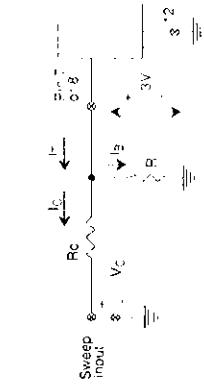


Figure 11. Circuit for Sine Wave Generation without External Adjustment. (See Figure 3 for Choice of R<sub>3</sub>)

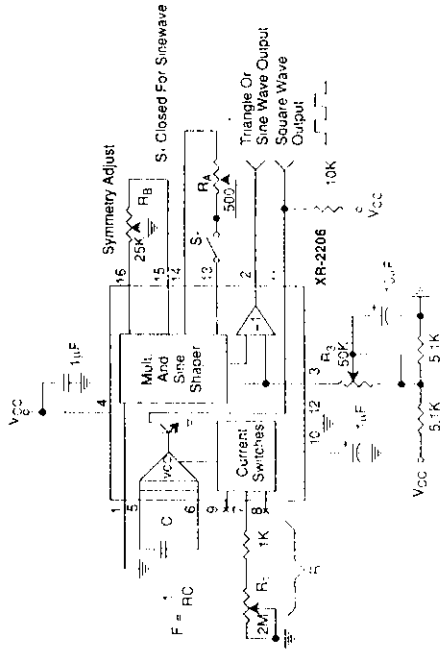


Figure 12. Circuit for Sine Wave Generation with Minimum Harmonic Distortion. (R<sub>3</sub> Determines Output Swing - See Figure 3)

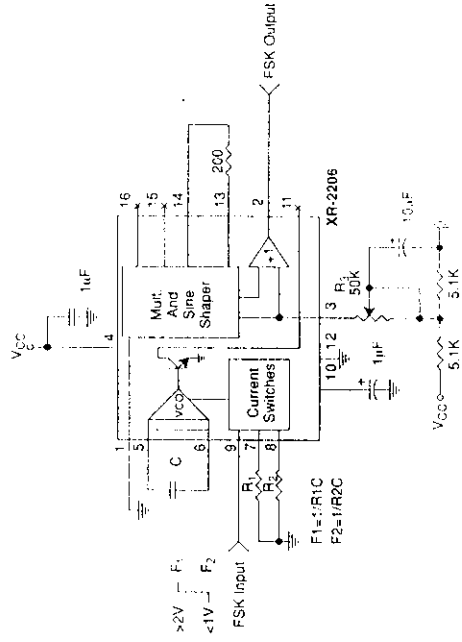


Figure 13. Sinusoidal FSK Generator



# National Semiconductor

## LM78XX Series Voltage Regulators

### General Description

The LM78XX series of three terminal regulators is available with several fixed output voltages making them useful in a wide range of applications. One of these is local on card regulation, eliminating the distribution problems associated with single point regulation. The voltages available allow these regulators to be used in logic systems, instrumentation, HiFi, and other solid state electronic equipment. Although designed primarily as fixed voltage regulators these devices can be used with external components to obtain adjustable voltages and currents.

The LM78XX series is available in an aluminum TO-3 package which will allow over 1.0A load current if adequate heat sinking is provided. Current limiting is included to limit the peak output current to a safe value. Safe area protection for the output transistor is provided to limit internal power dissipation. If internal power dissipation becomes too high for the heat sinking provided, the thermal shutdown circuit takes over preventing the IC from overheating.

Considerable effort was expended to make the LM78XX series of regulators easy to use and minimize the number

of external components. It is not necessary to bypass the output, although this does improve transient response. Input bypassing is needed only if the regulator is located far from the filter capacitor of the power supply.

For output voltage other than 5V, 12V and 15V the LM117 series provides an output voltage range from 1.2V to 57V.

### Features

- Output current in excess of 1A
- Internal thermal overload protection
- No external components required
- Output transistor safe area protection
- Internal short circuit current limit
- Available in the aluminum TO-3 package

### Voltage Range

- LM7805C 5V
- LM7812C 12V
- LM7815C 15V

### Absolute Maximum Ratings

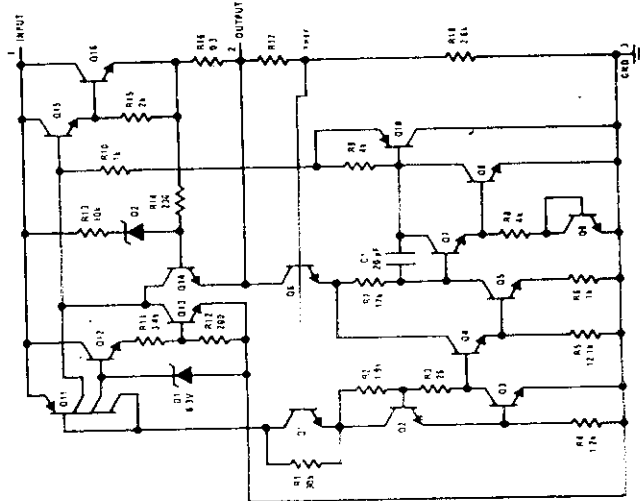
- Input Voltage (VO = 5V, 12V and 15V) 35V
- Internal Power Dissipation (Note 1) Internally Limited
- Operating Temperature Range (TA) 0°C to +70°C
- Maximum Junction Temperature (K Package) 150°C
- (T Package) 125°C
- Storage Temperature Range -65°C to +150°C
- Lead Temperature (Soldering, 10 seconds) 300°C
- TO-3 Package K 230°C
- TO-220 Package T

### Electrical Characteristics LM78XXC (Note 2) 0°C ≤ Tj ≤ 125°C unless otherwise noted.

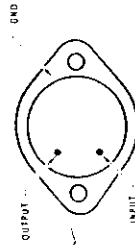
PARAMETER	5V			12V			15V		
	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX
VO Output Voltage	4.75	5.25	5.75	11.4	12.6	14.25	14.4	15	15.75
AVC Line Regulation	ΔVO/ΔVIN	3	50	4	120	4	150	4	150
	ΔVO/ΔVIN	17.3	20	14.6	20	17.7	20	17.7	20
AVO Load Regulation	ΔVO/ΔI	25	25	60	60	75	60	75	75
	ΔVO/ΔI	10	50	120	120	150	120	150	150
Quiescent Current	IO ≤ 1A	8.5	8.5	8.5	8.5	8.5	8.5	8.5	8.5
	5 mA ≤ IO ≤ 1A	0.5	0.5	0.5	0.5	0.5	0.5	0.5	0.5
Dropout Voltage	VO = 5V	1.0	1.0	1.0	1.0	1.0	1.0	1.0	1.0
	VO = 12V	1.0	1.0	1.0	1.0	1.0	1.0	1.0	1.0
Ripple Rejection	VO = 5V	62	62	55	55	54	54	54	54
	VO = 12V	62	62	55	55	54	54	54	54
Output Noise Voltage	TA = 25°C	40	40	75	75	90	75	90	90
	TA = 125°C	40	40	75	75	90	75	90	90
Input Voltage	VO = 5V	1.0	1.0	1.0	1.0	1.0	1.0	1.0	1.0
	VO = 12V	1.0	1.0	1.0	1.0	1.0	1.0	1.0	1.0
Line Regulation	ΔVO/ΔVIN	17.5	20	14.8	20	17.9	20	17.9	20
	ΔVO/ΔVIN	17	25	14.5	30	17.5	30	17.5	30
Dropout Voltage	VO = 5V	1.0	1.0	1.0	1.0	1.0	1.0	1.0	1.0
	VO = 12V	1.0	1.0	1.0	1.0	1.0	1.0	1.0	1.0
Output Resistance	VO = 5V	2.0	2.0	2.0	2.0	2.0	2.0	2.0	2.0
	VO = 12V	2.0	2.0	2.0	2.0	2.0	2.0	2.0	2.0
Short-Circuit Current	VO = 5V	2.1	2.1	2.1	2.1	2.1	2.1	2.1	2.1
	VO = 12V	2.1	2.1	2.1	2.1	2.1	2.1	2.1	2.1
Peak Output Current	VO = 5V	0.6	0.6	0.6	0.6	0.6	0.6	0.6	0.6
	VO = 12V	0.6	0.6	0.6	0.6	0.6	0.6	0.6	0.6
Average TC of VOUT	VO = 5V	7.3	7.3	14.6	14.6	17.7	17.7	17.7	17.7
	VO = 12V	7.3	7.3	14.6	14.6	17.7	17.7	17.7	17.7

NOTE 1: Thermal resistance of the TO-3 package (K, KC) is typically 4°C/W junction to case and 35°C/W case to ambient. Thermal resistance of TO-220 package (T) is typically 4°C/W junction to case and 50°C/W case to ambient.  
 NOTE 2: All characteristics are measured with capacitor across the input of 0.22 μF, and a capacitor across the output of 0.1 μF. All characteristics are measured using pulse techniques (tw ≤ 10 ms, duty cycle ≤ 5%). Output voltage changes due to changes in internal temperature must be taken into account separately.

### Schematic and Connection Diagrams

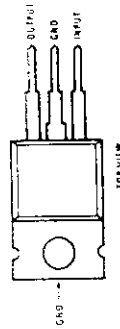


Metal Can Package TO-3 (K) Aluminum



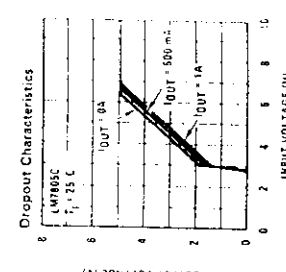
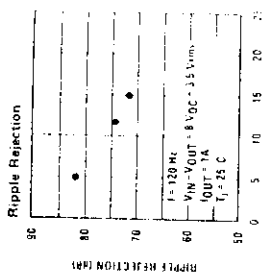
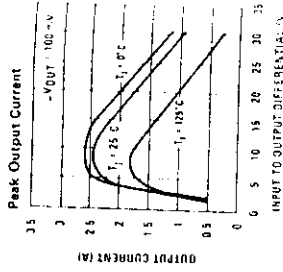
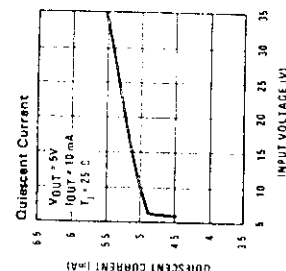
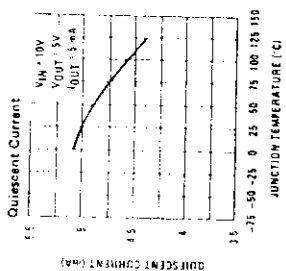
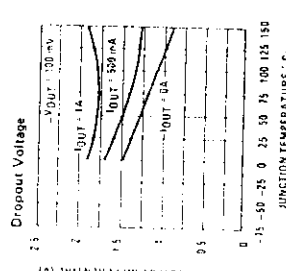
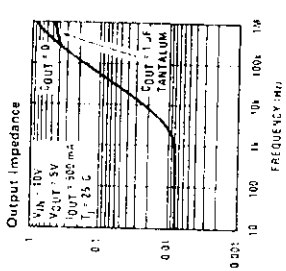
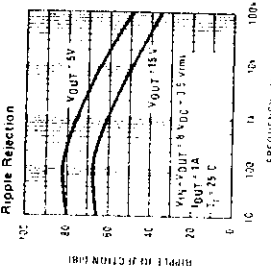
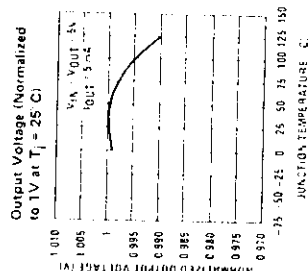
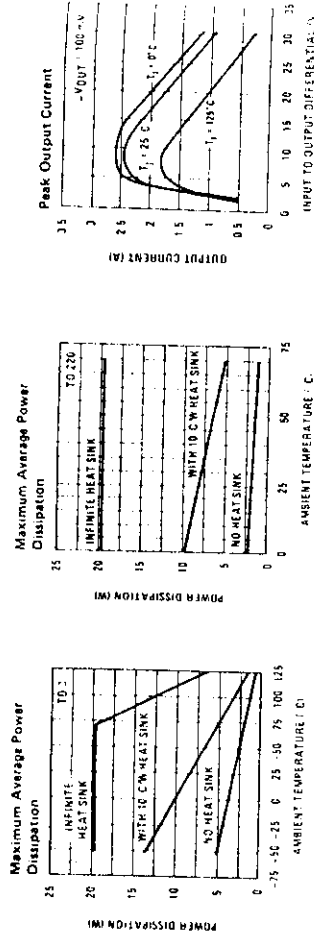
Order Numbers LM7805CK LM7812CK LM7815CK See Package KC02A

Plastic Package TO-220 (T)



Order Numbers: LM7805CT LM7812CT LM7815CT See Package T03B

### Typical Performance Characteristics



# National Semiconductor

## Voltage Regulators

### LM78LXX Series 3-Terminal Positive Regulators

#### General Description

The LM78LXX series of three terminal positive regulators is available with several fixed output voltages making them useful in a wide range of applications. When used as a zener diode/resistor combination replacement, the LM78LXX usually results in an effective output impedance improvement of two orders of magnitude, and lower quiescent current. These regulators can provide local on card regulation, eliminating the distribution problems associated with single point regulation. The voltages available allow the LM78LXX to be used in logic systems, instrumentation, HiFi, and other solid state electronic equipment. Although designed primarily as fixed voltage regulators these devices can be used with external components to obtain adjustable voltages and currents.

The LM78LXX is available in the metal three lead TO-5 (H1) and the plastic TO-92 (Z). With adequate heat sinking the regulator can deliver 100 mA output current. Current limiting is included to limit the peak output current to a safe value. Safe area protection for the output transistor is provided to limit internal power dissipation. If internal power dissipation becomes

too high for the heat sinking provided, the thermal shutdown circuit takes over preventing the IC from overheating.

For output voltage other than 5V, 12V and 15V the LM117 series provides an output voltage range from 1.2V to 57V.

#### Features

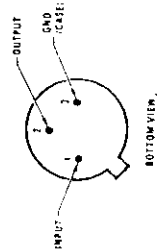
- Output voltage tolerances of  $\pm 5\%$  (LM78LXXAC) and  $\pm 10\%$  (LM78LXXC) over the temperature range
- Output current of 100 mA
- Internal thermal overload protection
- Output transistor safe area protection
- Internal short circuit current limit
- Available in plastic TO-92 and metal TO-39 low profile packages

#### Voltage Range

- LM78L05 5V
- LM78L12 12V
- LM78L15 15V

#### Connection Diagrams

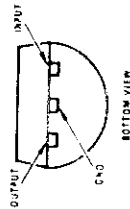
Metal Can Package



Order Numbers:

- LM78L05ACH LM78L05CH
  - LM78L12ACH LM78L12CH
  - LM78L15ACH LM78L15CH
- See Package H03A

Plastic Package



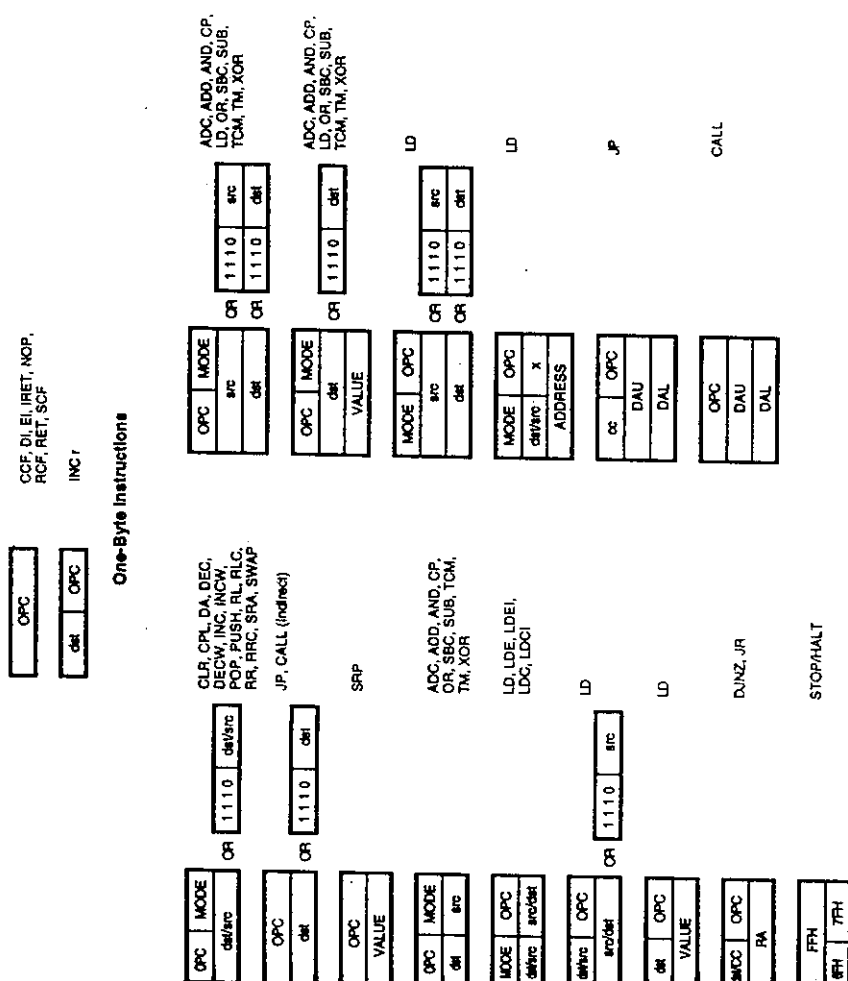
Order Numbers:

- LM78L05ACZ LM78L05CZ
  - LM78L12ACZ LM78L12CZ
  - LM78L15ACZ LM78L15CZ
- See Package Z03A

CONDITION CODES

Value	Mnemonic	Meaning	Flags Set
1000	---	Always true	---
0111	C	Carry	C=1
1111	NC	No Carry	C=0
0110	Z	Zero	Z=1
1110	NZ	Not zero	Z=0
1101	PL	Plus	S=0
0101	MI	Minus	S=1
0100	OV	Overflow	V=1
1100	NOV	No overflow	V=0
0110	EQ	Equal	Z=1
1110	NE	Not equal	Z=0
1001	GE	Greater than or equal	(S XOR V)=0
0001	LT	Less than	(S XOR V)=1
1010	GT	Greater than	(Z OR (S XOR V))=0
0010	LE	Less than or equal	(Z OR (S XOR V))=1
1111	UGE	Unsigned greater than or equal	C=0
0111	ULT	Unsigned less than	C=1
1011	UGT	Unsigned greater than	(C = 0 AND Z=0)=1
0011	ULE	Unsigned less than or equal	(C OR Z)=1
0000	F	Never true (Always False)	...

INSTRUCTION FORMATS



INSTRUCTION SUMMARY

Note: Assignment of a value is indicated by the symbol '+'-. For example:

dst ← dst + src

dst(7)

refers to bit 7 of the destination operand.



**INSTRUCTION SET NOTATION**

**Addressing Modes.** The following notation is used to describe the addressing modes and instruction operations as shown in the instruction summary.

Symbol	Meaning
RR	Indirect register pair or indirect working-register pair address
r	Indirect working-register pair only
X	Indexed address
DA	Direct address
RA	Relative address
IM	Immediate
R	Register or working-register address
r	Working register address only
R	Indirect-register or indirect working-register address
r	Indirect working-register address only
RR	Register pair or working register pair address

**Flags.** Control register (R252) contains the following six flags.

Symbol	Meaning
C	Carry flag
Z	Zero flag
S	Sign flag
V	Overflow flag
D	Decimal-adjust flag
H	Half-carry flag

Affected flags are indicated by:

0	Clear to zero
1	Set to one
.	Set to clear according to operation
-	Unaffected
X	Undefined

**Symbols.** The following symbols are used in describing the instruction set.

Symbol	Meaning
DR	Destination location or contents
SR	Source location or contents
CC	Condition code
EA	Indirect address prefix
SP	Stack pointer
PC	Program counter
FLAGS	Flag register (Control Register 252)
IP	Register Pointer (R253)
IMR	Interrupt mask register (R251)

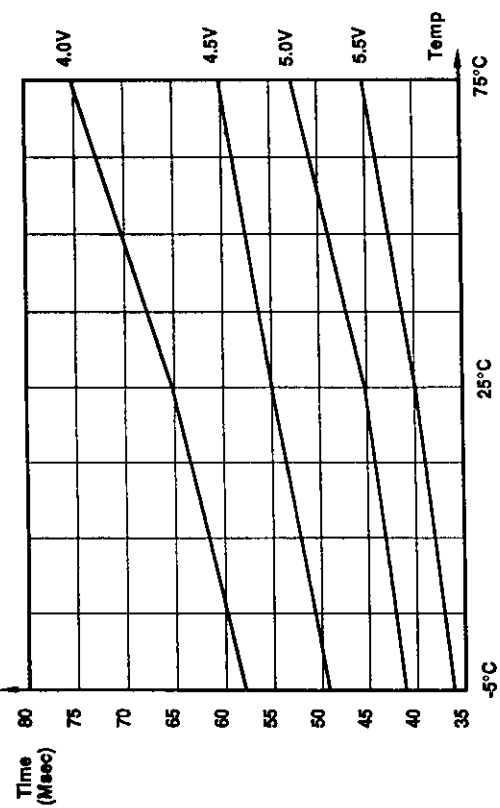


Figure 42. Typical POR Time Out Period vs Temperature

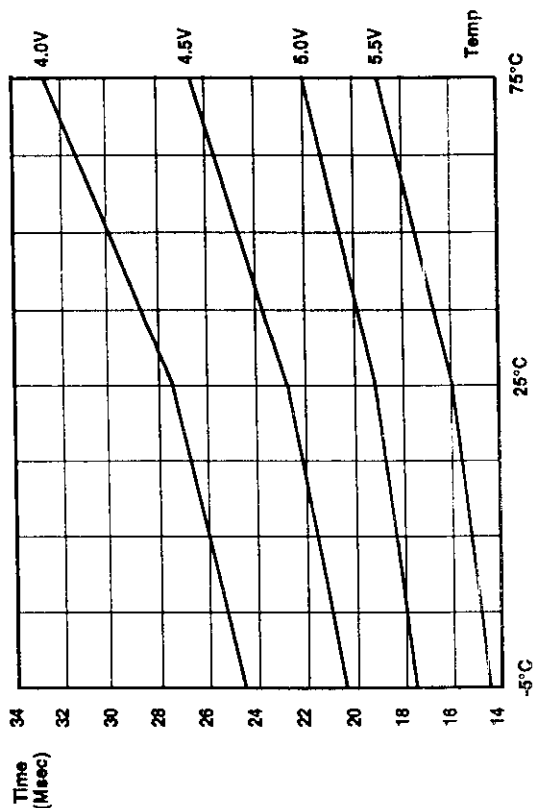


Figure 43. Typical WDT Time Out Period vs Temperature

CONTROL REGISTERS

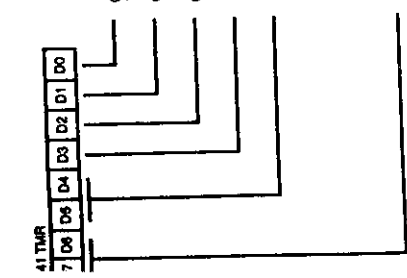


Figure 24. Timer Mode Register (F1H: Read/Write)

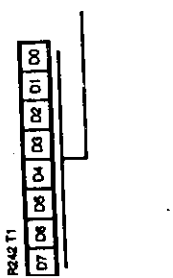


Figure 25. Counter/Timer 1 Register (F2H: Read/Write)

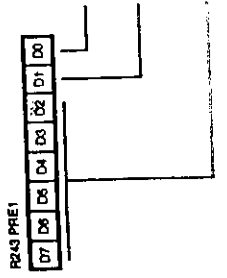


Figure 26. Prescaler 1 Register (F3H: Write Only)



Figure 27. Counter/Timer 0 Register (F4H: Read/Write)

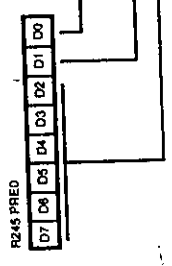


Figure 28. Prescaler 0 Register (F5H: Write Only)

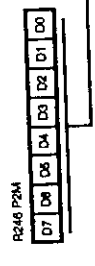


Figure 29. Port 2 Mode Register (F6H: Write Only)

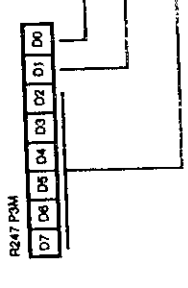


Figure 30. Port 3 Mode Register (F7H: Write Only)



Figure 31. Port 0 and 1 Mode Register (F8H: Write Only)

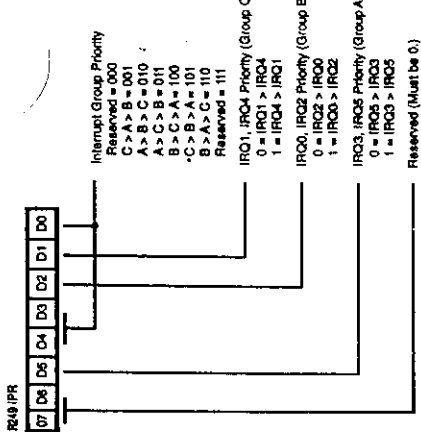


Figure 32. Interrupt Priority Register (F9H: Write Only)

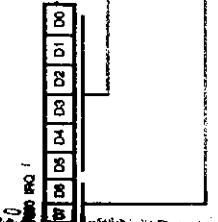


Figure 33. Interrupt Request Register (FAH: Read/Write)

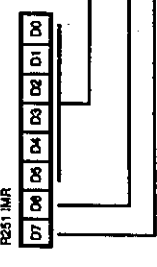


Figure 34. Interrupt Mask Register (FBH: Read/Write)

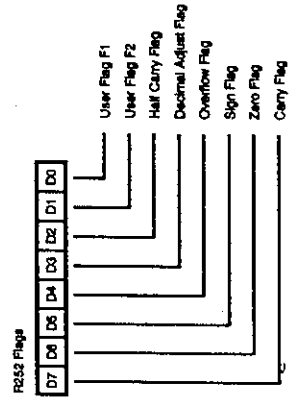


Figure 35. Flag Register (FCH: Read/Write)

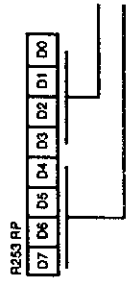


Figure 36. Register Pointer (FDH: Read/Write)

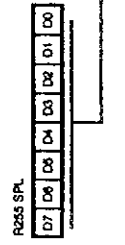


Figure 37. Stack Pointer (FFH: Read/Write)

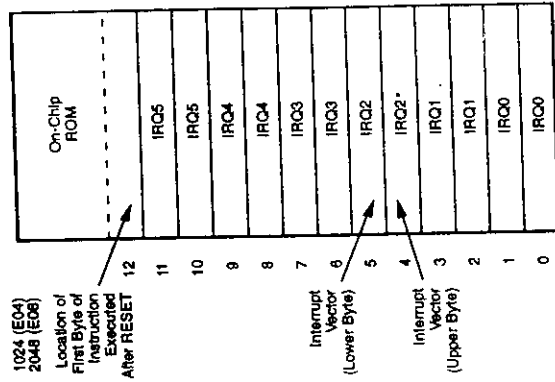
**SPECIAL FUNCTIONS (Continued)**

**Table 4. Z86E04/08 Control Registers**

Addr. Reg.	Reset Condition								Comments
	D7	D6	D5	D4	D3	D2	D1	D0	
F1	0	0	0	0	0	0	0	0	
F2	U	U	U	U	U	U	U	U	
F3	PRE1	U	U	U	U	U	U	0	
F4	T0	U	U	U	U	U	U	U	
F5	PRE0	U	U	U	U	U	U	U	
F6*	P2M	1	1	1	1	1	1	1	Inputs after reset.
F7*	P3M	U	U	U	U	U	U	0	
F8*	P01M	U	U	U	U	U	U	0	
F9	IPR	U	U	U	U	U	U	U	
FA	IRQ	U	0	0	0	0	0	0	IRQ3 is used for positive edge detection.
PB	IMR0	U	U	U	U	U	U	U	
PC	FLAGS	U	U	U	U	U	U	U	
FD	RP	0	0	0	0	0	0	0	
FF	SPLU	U	U	U	U	U	U	U	

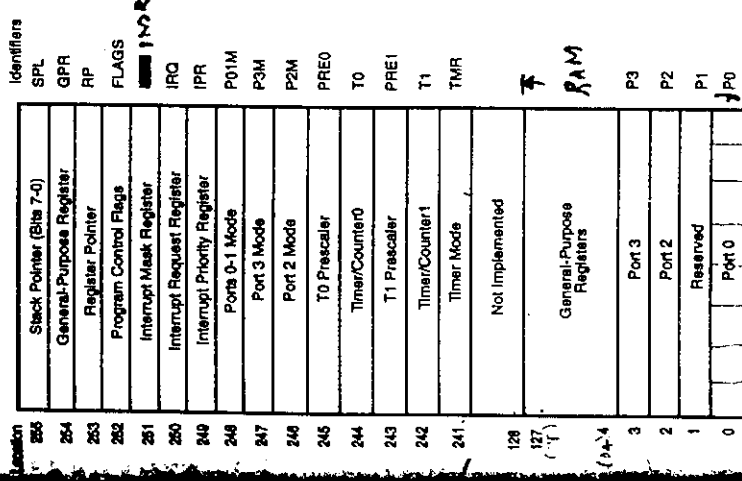
**Note:**  
 \* Registers are not reset after a Stop-Mode Recovery using P27 pin. A subsequent reset will cause these control registers to be reconfigured as shown in Table 4 and the user must avoid bus contention on the port pins or it may affect device reliability.

**Program Memory.** The Z86E04/08 addresses up to 1K bytes of internal program memory (Figure 10). The first bytes of program memory are reserved for the interrupt vectors. These locations contain six 16-bit vectors that correspond to the six available interrupts. Bytes 0-1024 are on-chip one-time programmable ROM.



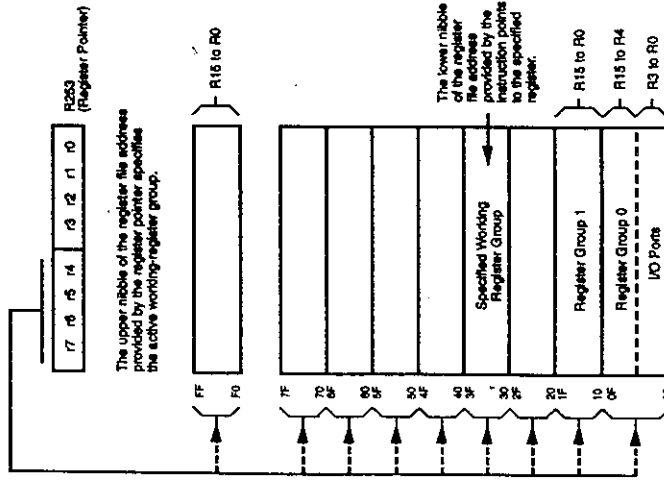
**Figure 10. Program Memory Map**

**Register File.** The Register File consists of three I/O port registers, 124 general-purpose registers, and 14 control and status registers R0-R3, R4-R127 and R241-R255, respectively (Figure 11). General-purpose registers occupy the 04H to 7FH address space. I/O ports are mapped as per the existing CMOS Z8. The Z86E04/08 instructions can access registers directly or indirectly through an 8-bit



**Figure 11. Register File**

address field. This allows short 4-bit register addressing using the Register Pointer. In the 4-bit mode, the register file is divided into eight working register groups, each occupying 16 continuous locations. The Register Pointer (Figure 12) addresses the starting location of the active working-register group.



**Figure 12. Register Pointer**